

In-Situ Hard X-ray Ptychography

Workshop on Coherence at ESRF-EBS

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Germany

HELMHOLTZ RESEARCH FOR
GRAND CHALLENGES

PtyNAMi
Ptychographic Nano-Analytical Microscope

GEFÖRDERT VOM



Bundesministerium
für Bildung
und Forschung



X-Ray Nanoscience and X-Ray Optics



Prof. Dr. Christian G. Schroer (DESY and Universität Hamburg)
Dr. Gerald Falkenberg (DESY - P06 beamline responsible)

S. Alizadehfanaloo, T. Böse, S. Botta, D. Brückner, R. Döhrmann, J. Garrevoet, J. Hagemann, M. Kahnt, M. Lyubomirskiy, C. Ossig, M. Scholz, A. Schropp, W. Schröder, F. Seiboth, M. Seyrich, K. Spiers, M. Stückelberger, P. Wiljes, F. Wittwer, and X. Yang

Scanning coherent X-ray microscopy, using fluorescence (XRF), diffraction (SAXS, WAXS), absorption (XAS) and ptychographic (CXDI) contrast.



PETRA III (DESY, Hamburg)



LCLS (SLAC, Menlo Park)



European XFEL (Schenefeld)

PETRA III: DESY's Brilliant Hard X-ray Source



- > particle energy: 6 GeV
- > stored current: 100 mA (top-up)
- > emittance: 1.2 nm rad
- > circumference: 2304 m
- > # of undulators: 25 (incl. canted)
- > # of experiments: 50
- > X-ray wavelength: 10 – 0.05 Å
- > annual operation: 5000 h (for users)

- > built in 1978 for high-energy physics
- > rebuilt as a synchrotron radiation source starting in 2007
- > user operation since 2010
- > extension added: March 2014 - April 2015

PETRA III: X-Ray Microscopy

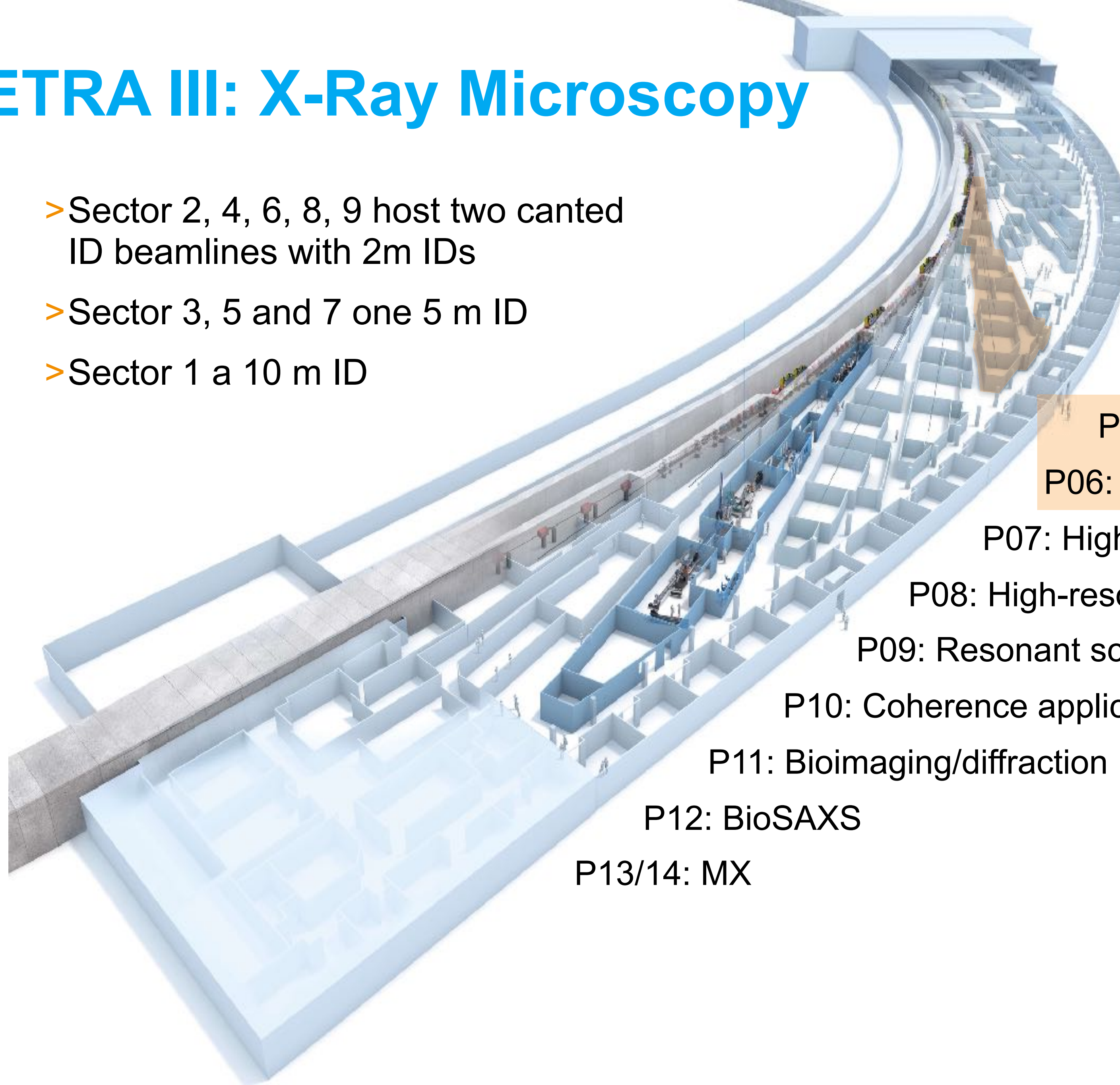
- > Sector 2, 4, 6, 8, 9 host two canted ID beamlines with 2m IDs
- > Sector 3, 5 and 7 one 5 m ID
- > Sector 1 a 10 m ID

- P01: Dynamics beamline, IXS, NRS
- P02: Powder diffraction/Extreme Conditions
- P03: Micro-, nano-SAXS, WAXS
- P04: Variable polarization XUV
- P05: Micro-, nano-tomography
- P06: Hard x-ray micro-, nanoprobe
- P07: High energy materials science
- P08: High-resolution diffraction
- P09: Resonant scattering/diffraction
- P10: Coherence applications
- P11: Bioimaging/diffraction
- P12: BioSAXS
- P13/14: MX

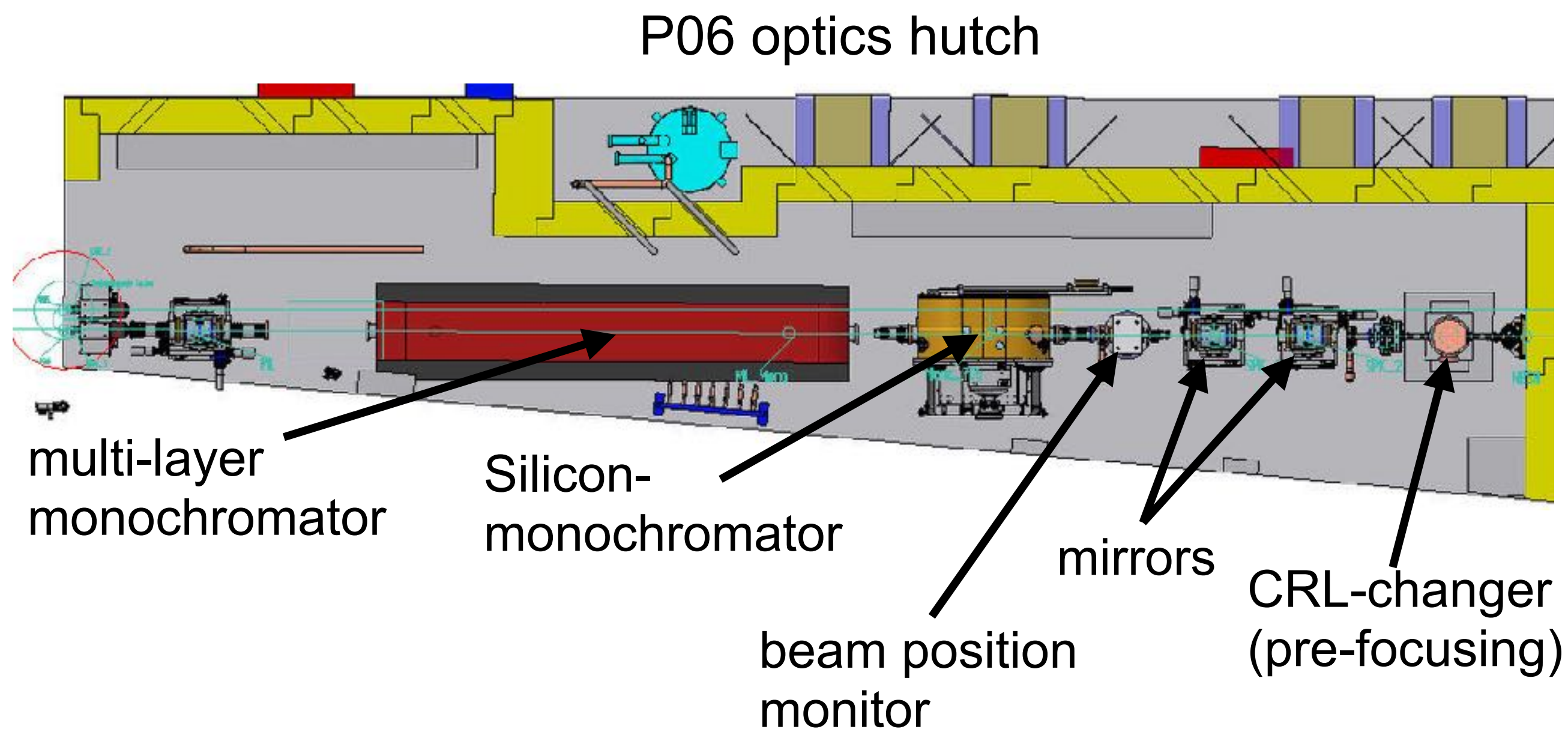
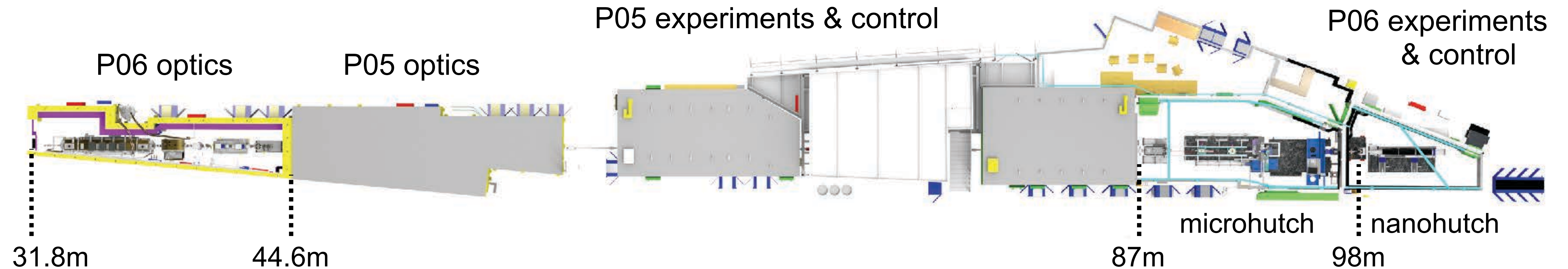
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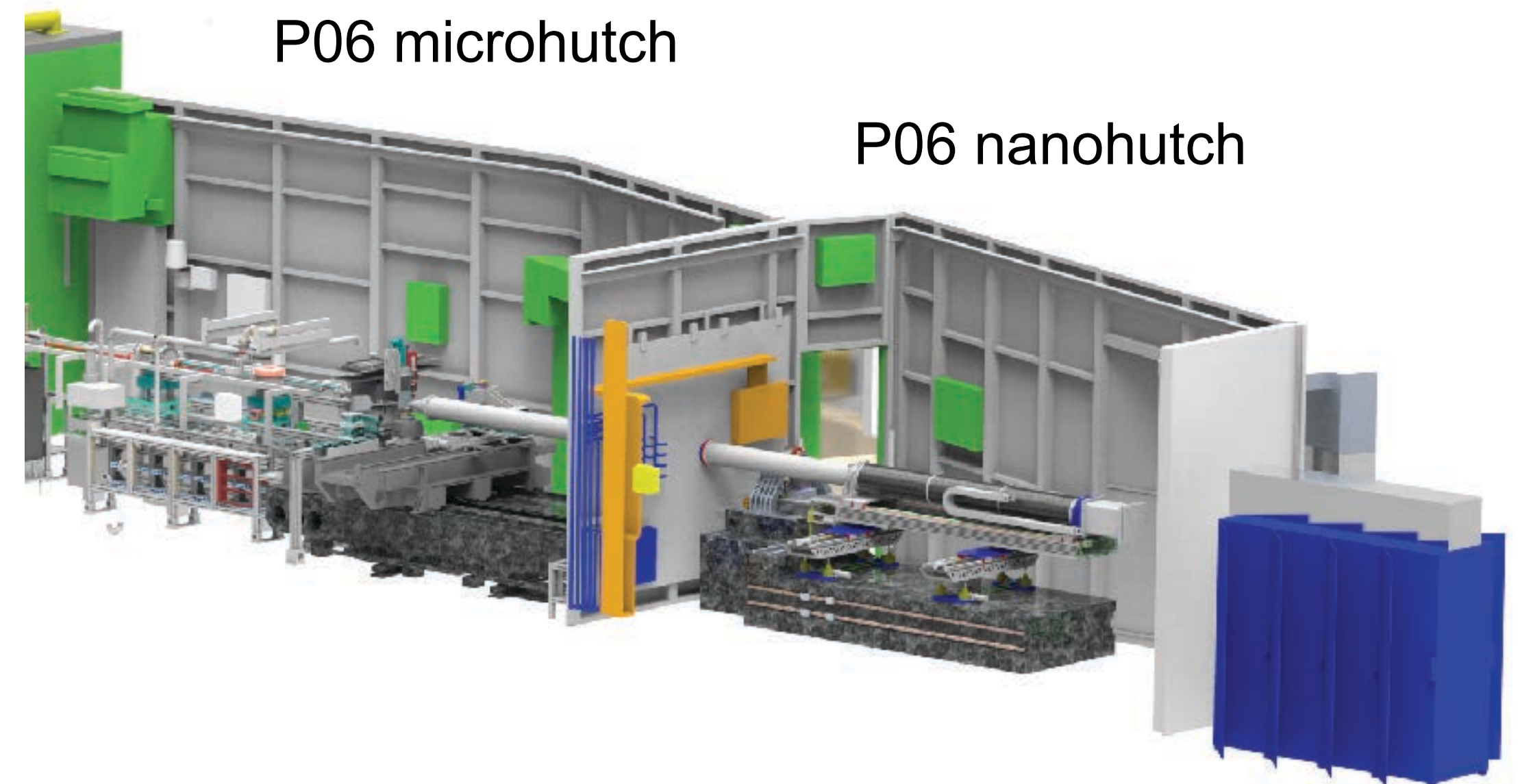
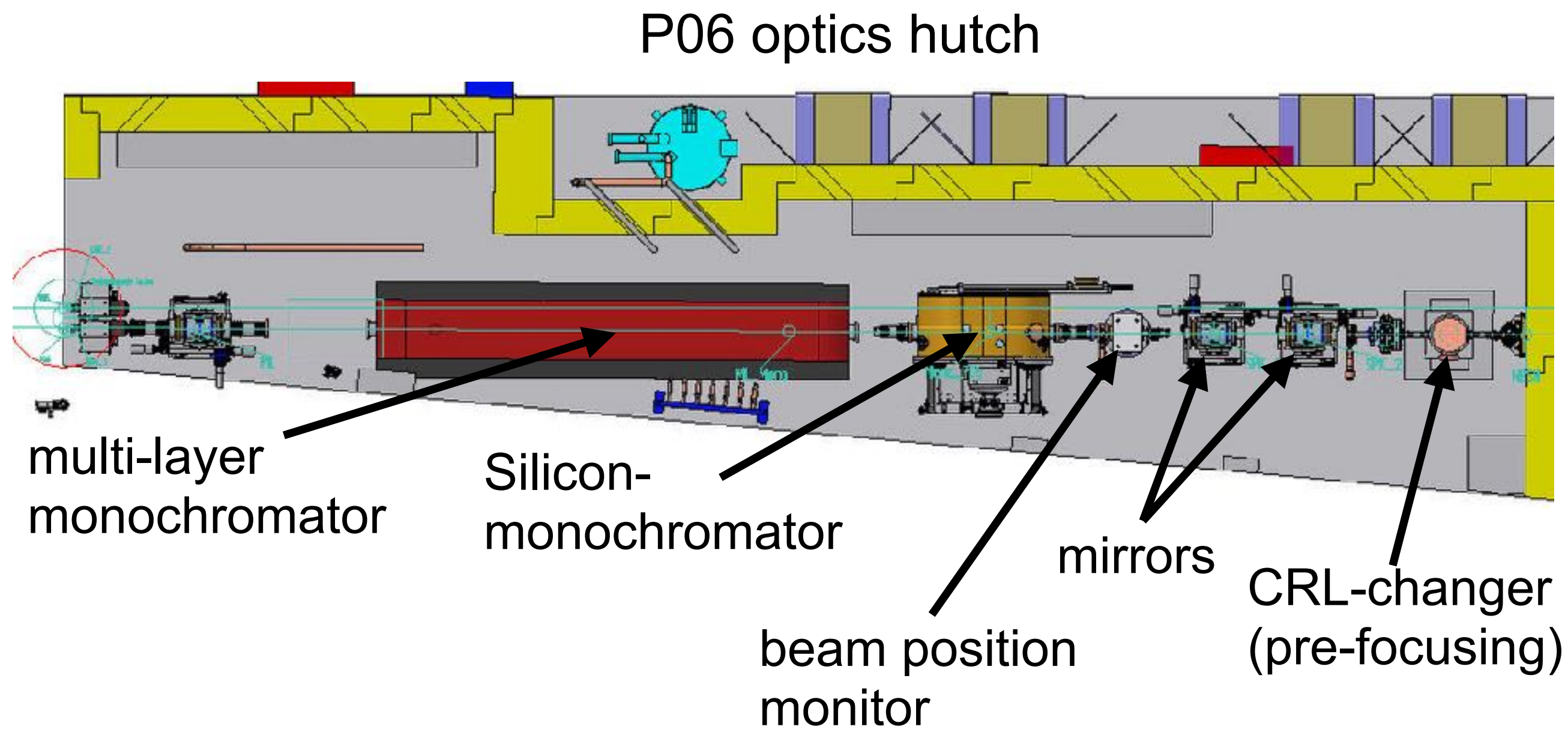
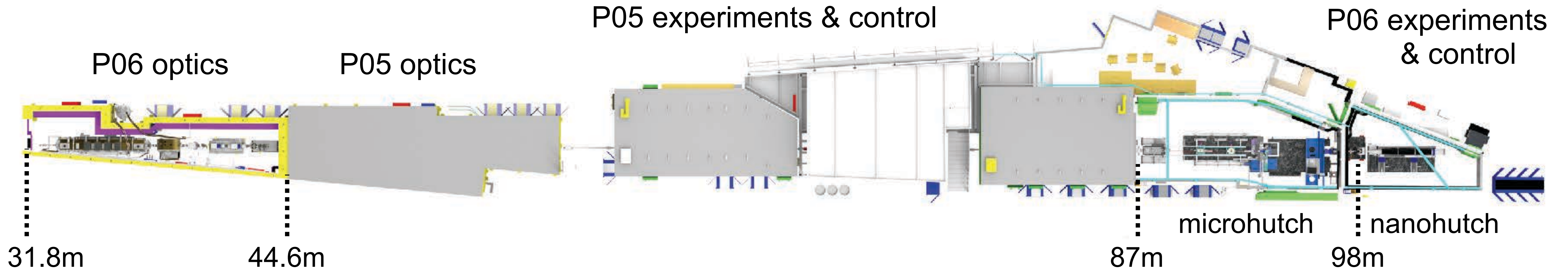


Beamline P06 at PETRA III



- > monochromators:
 - Si(111)-channelcut (CC)
 - Si(111)-double crystal monochromator (DCM)
 - multilayer-monochromator (ML)
- > horizontal offset mirrors (HO-mirrors)
- > pre-focusing: CRL-changer

Beamline P06 at PETRA III

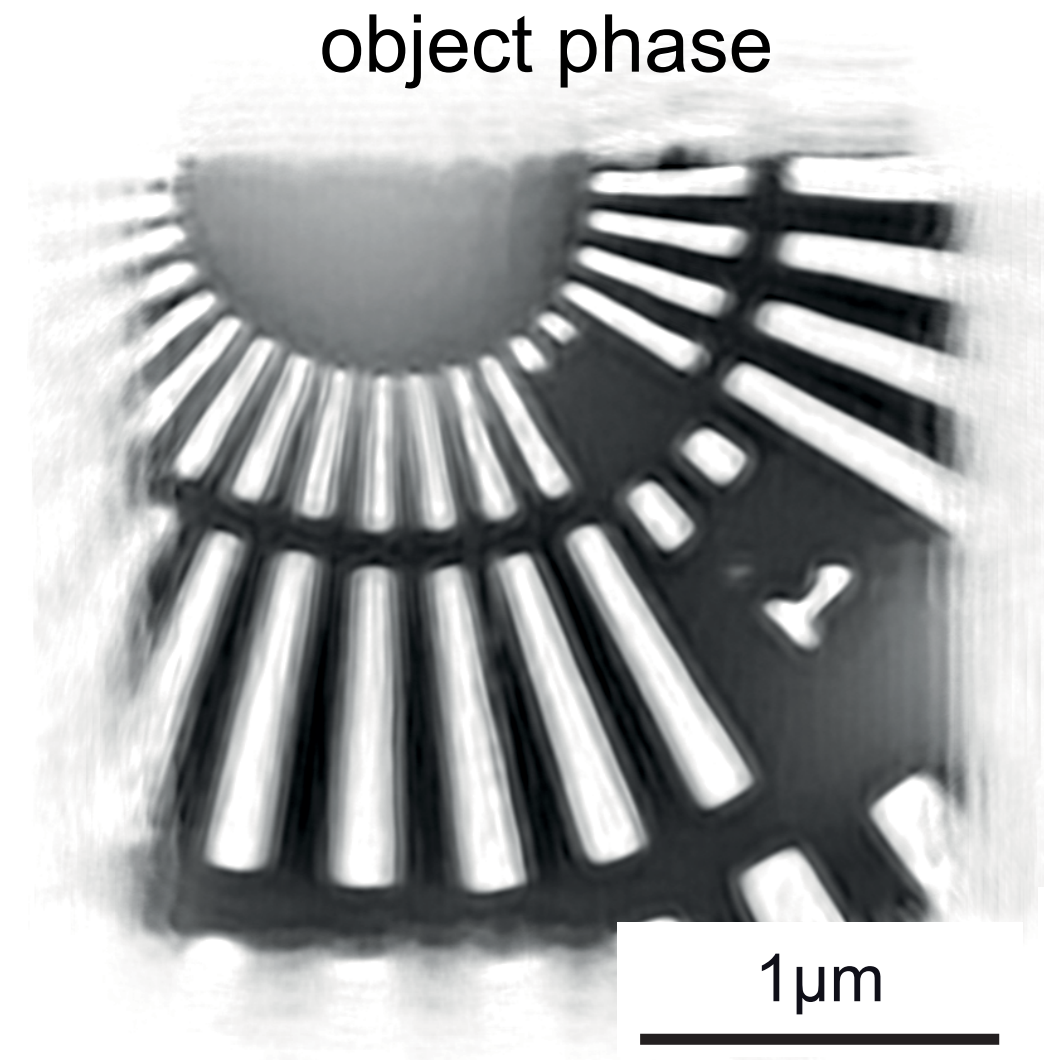


Nanoprobe Setup at Beamline P06 (2015)

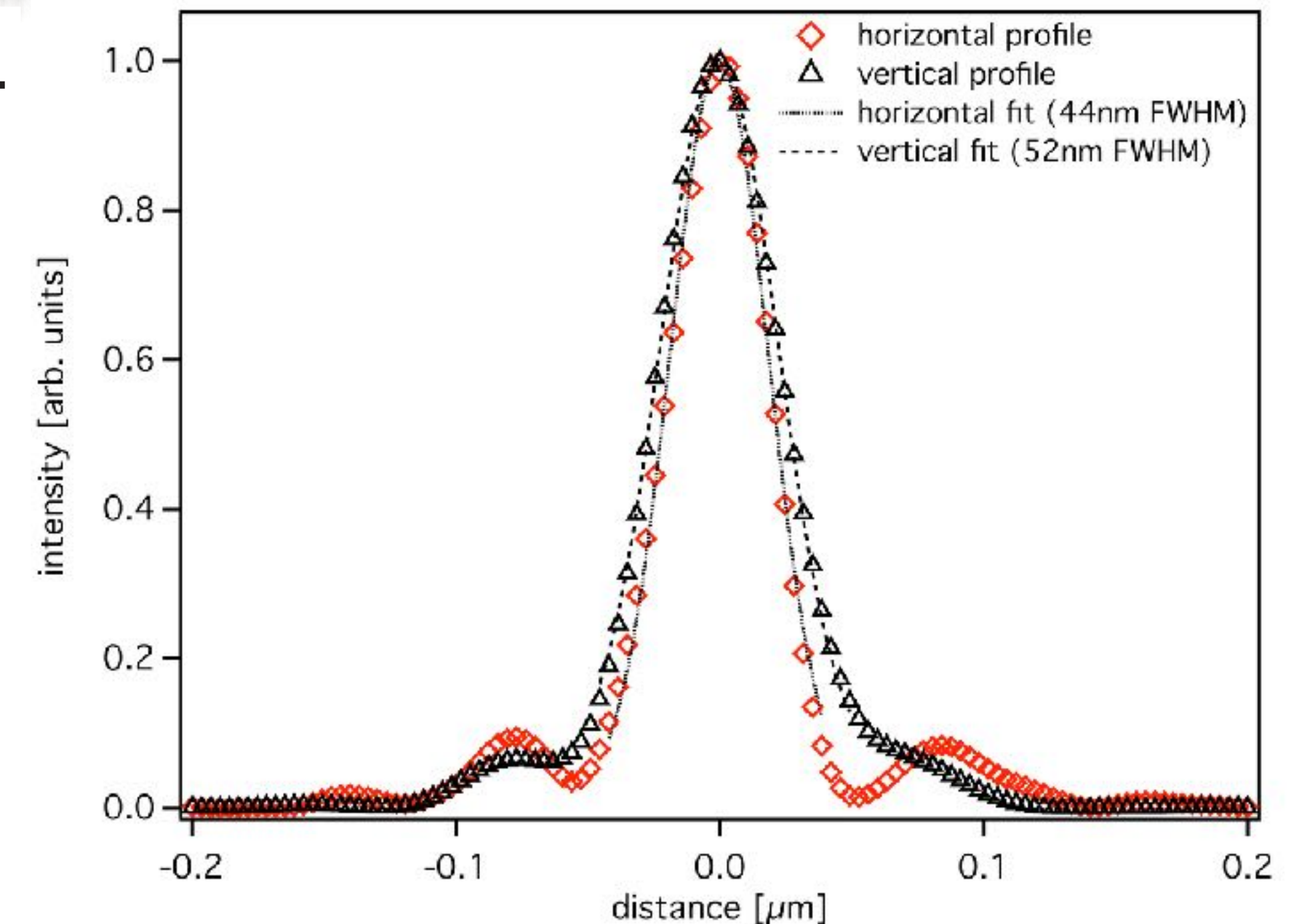
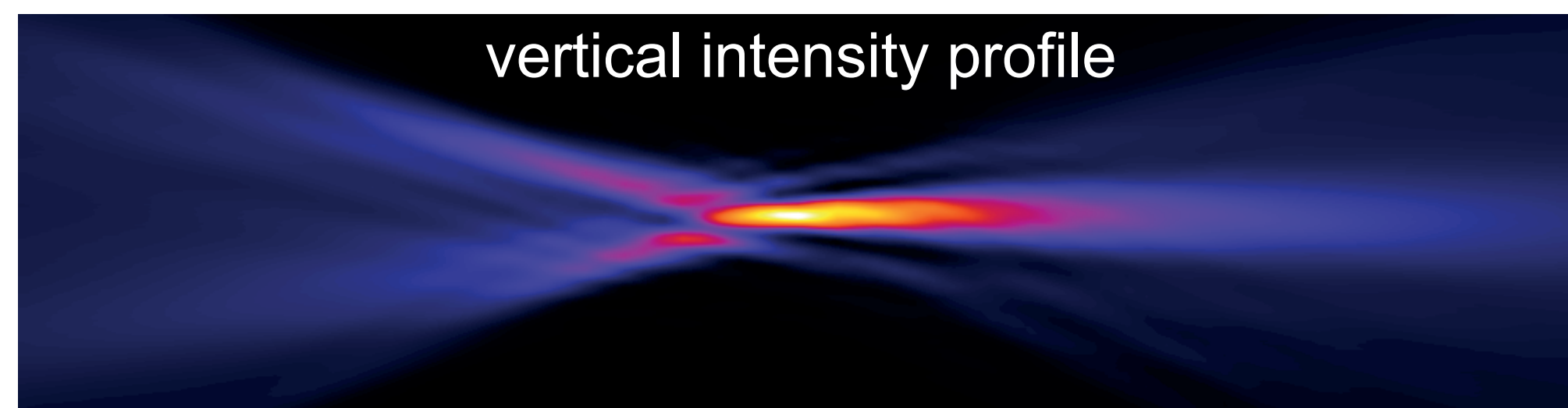
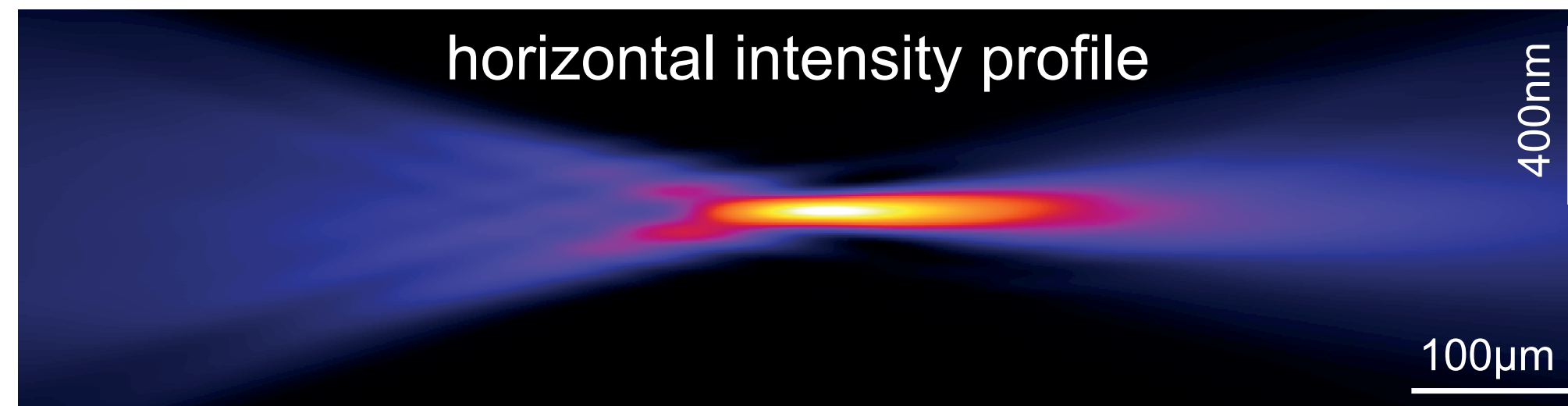
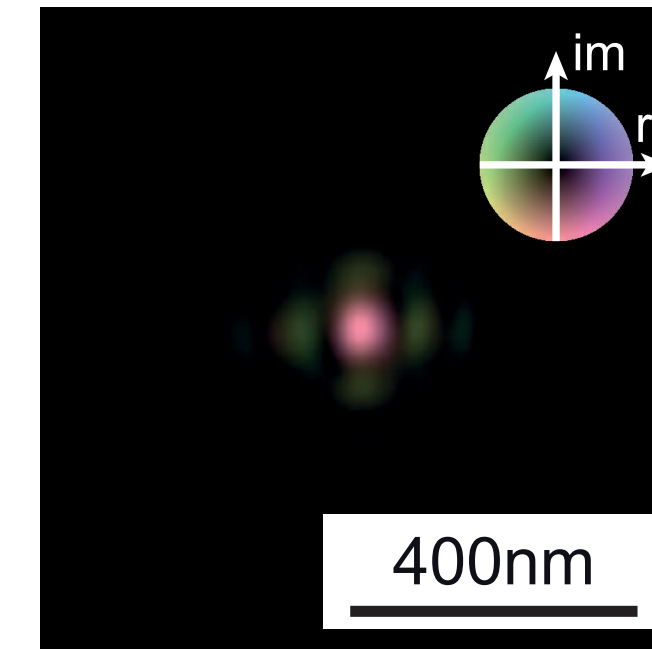


Nanobeam Characterization by Ptychography

- > X-ray energy: 18 keV
- > convergence after 200 iterations
- > focus size 44 nm x 52 nm (FWHM)
- > almost perfect nano-focused X-ray beam

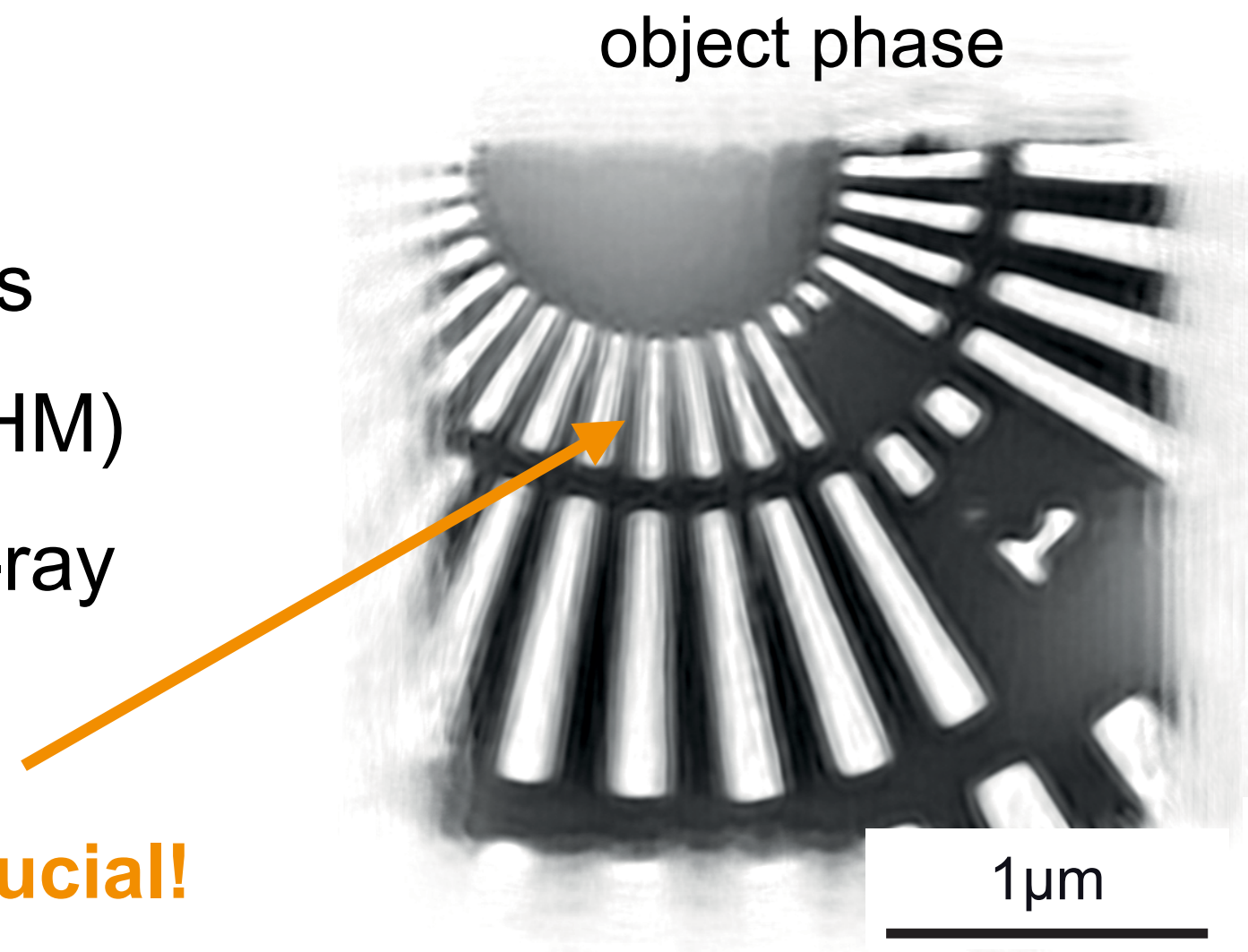


illumination function

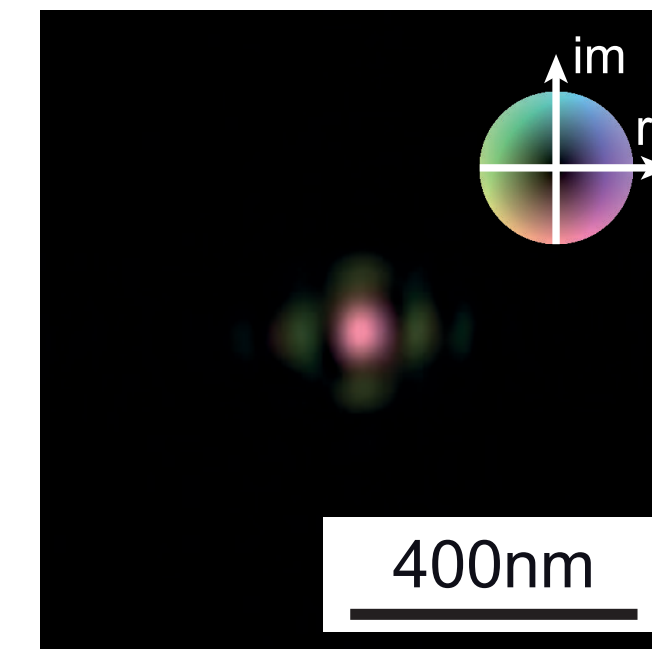


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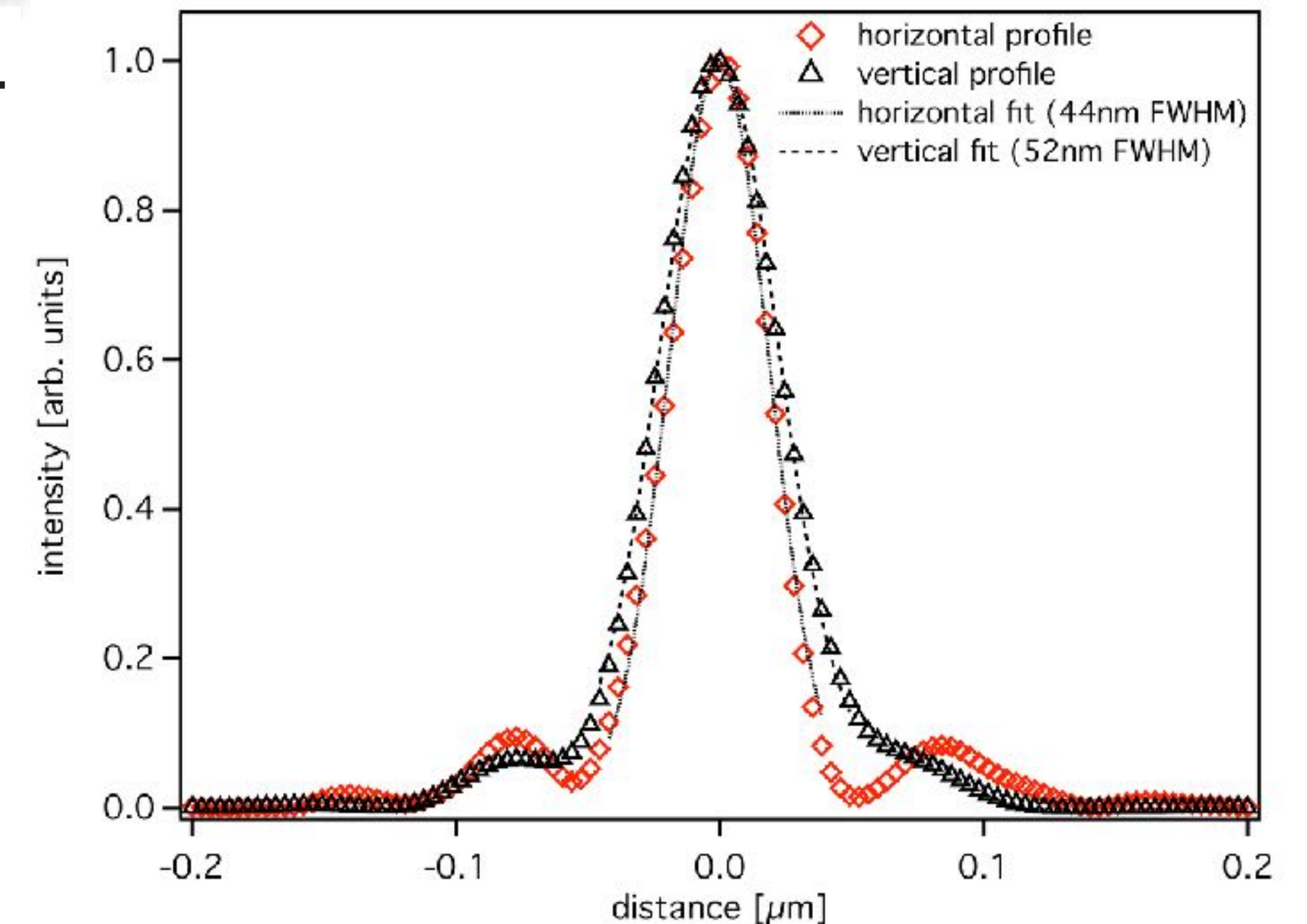
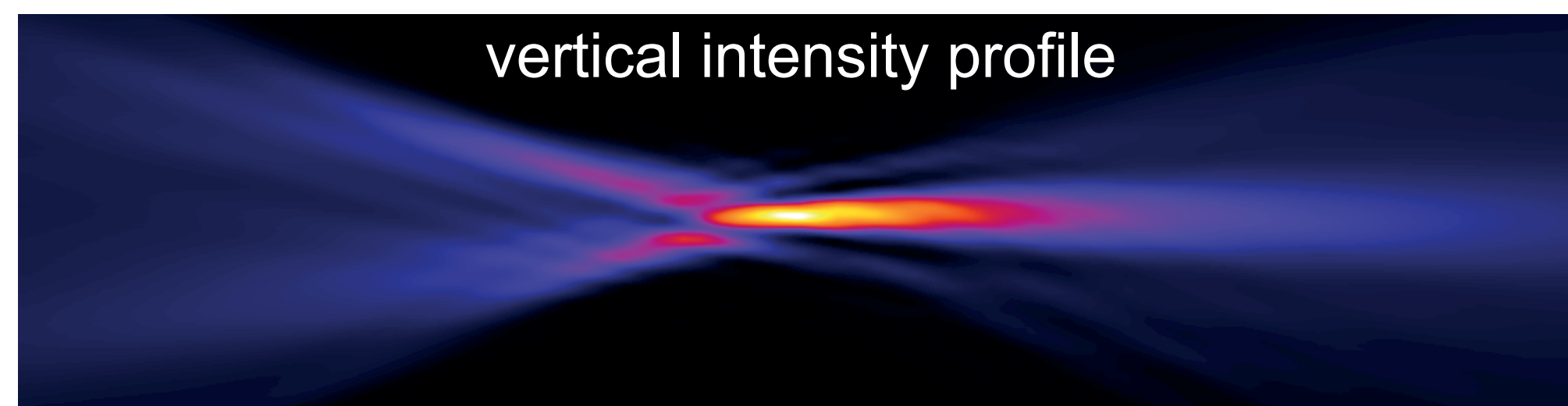
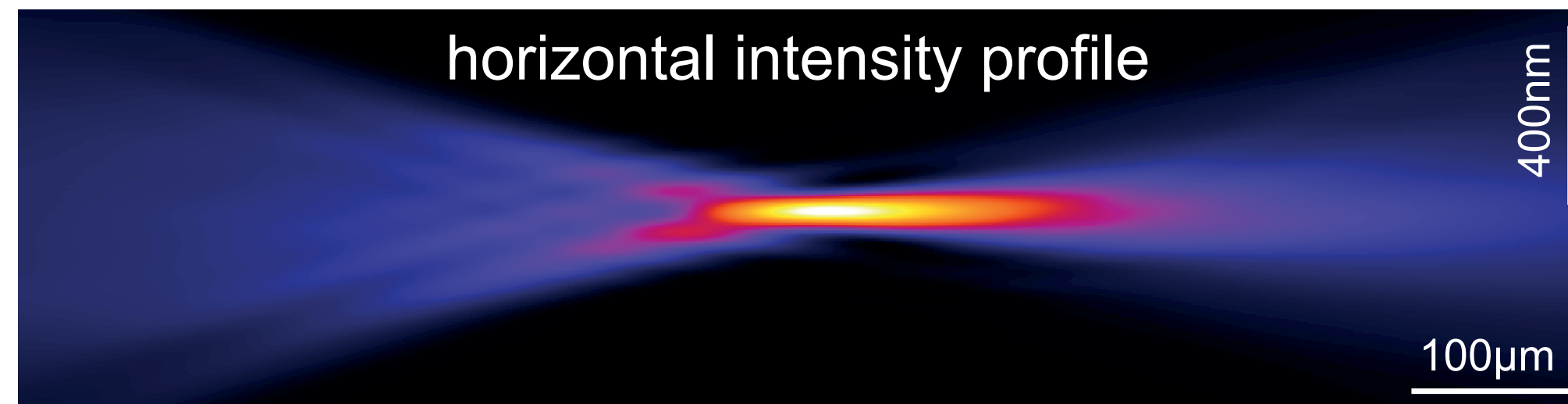
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Stability of the setup crucial!



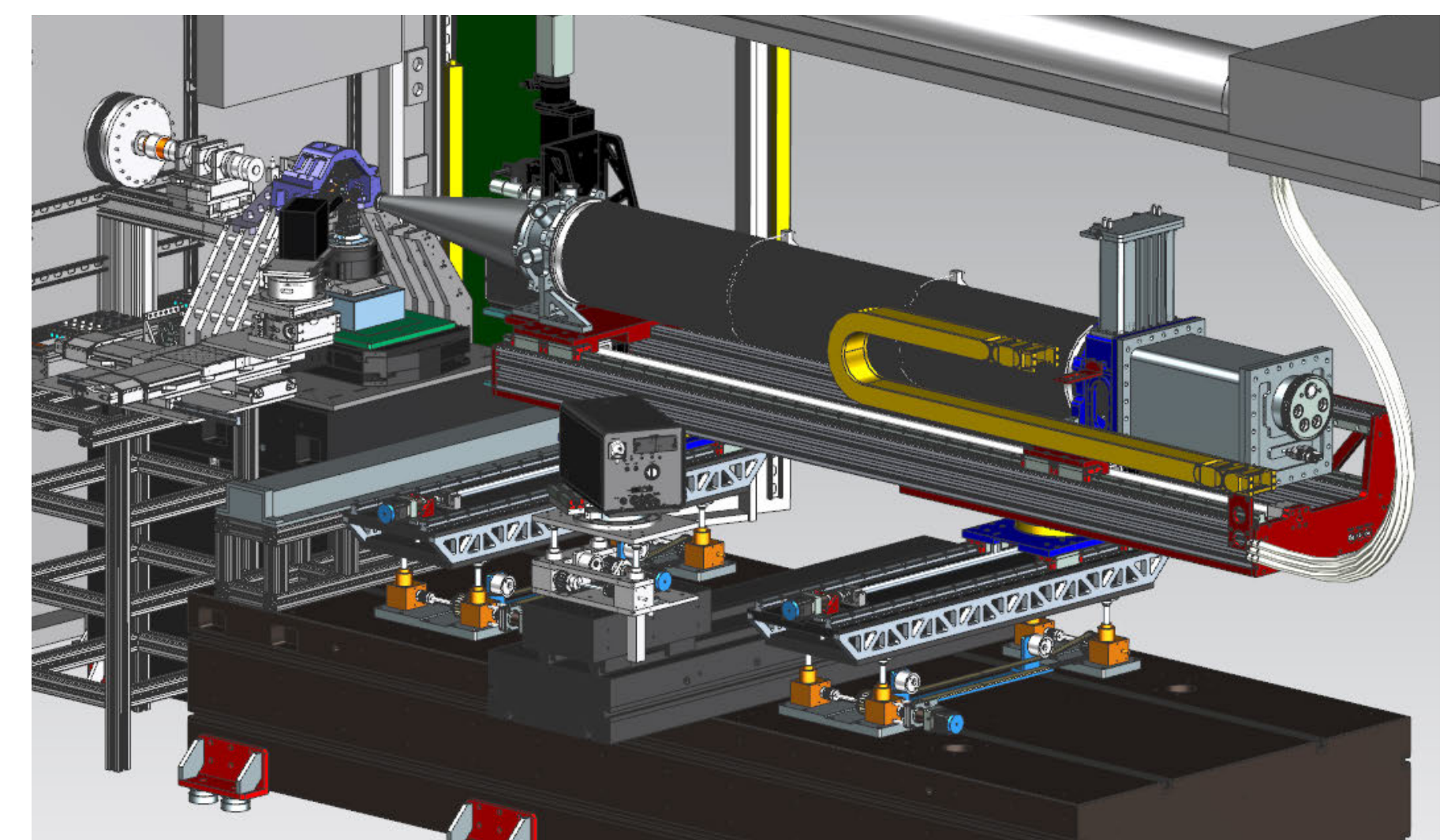
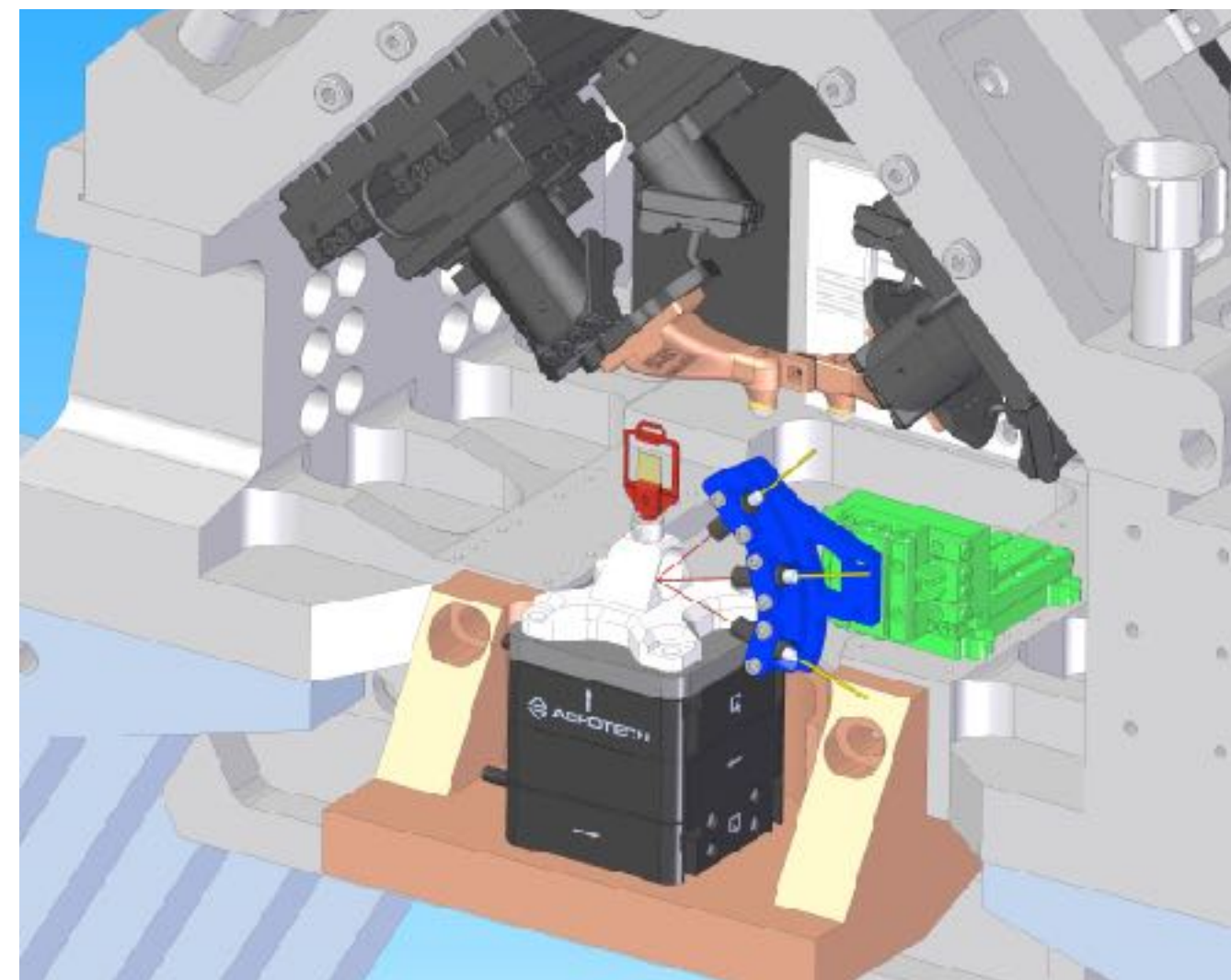
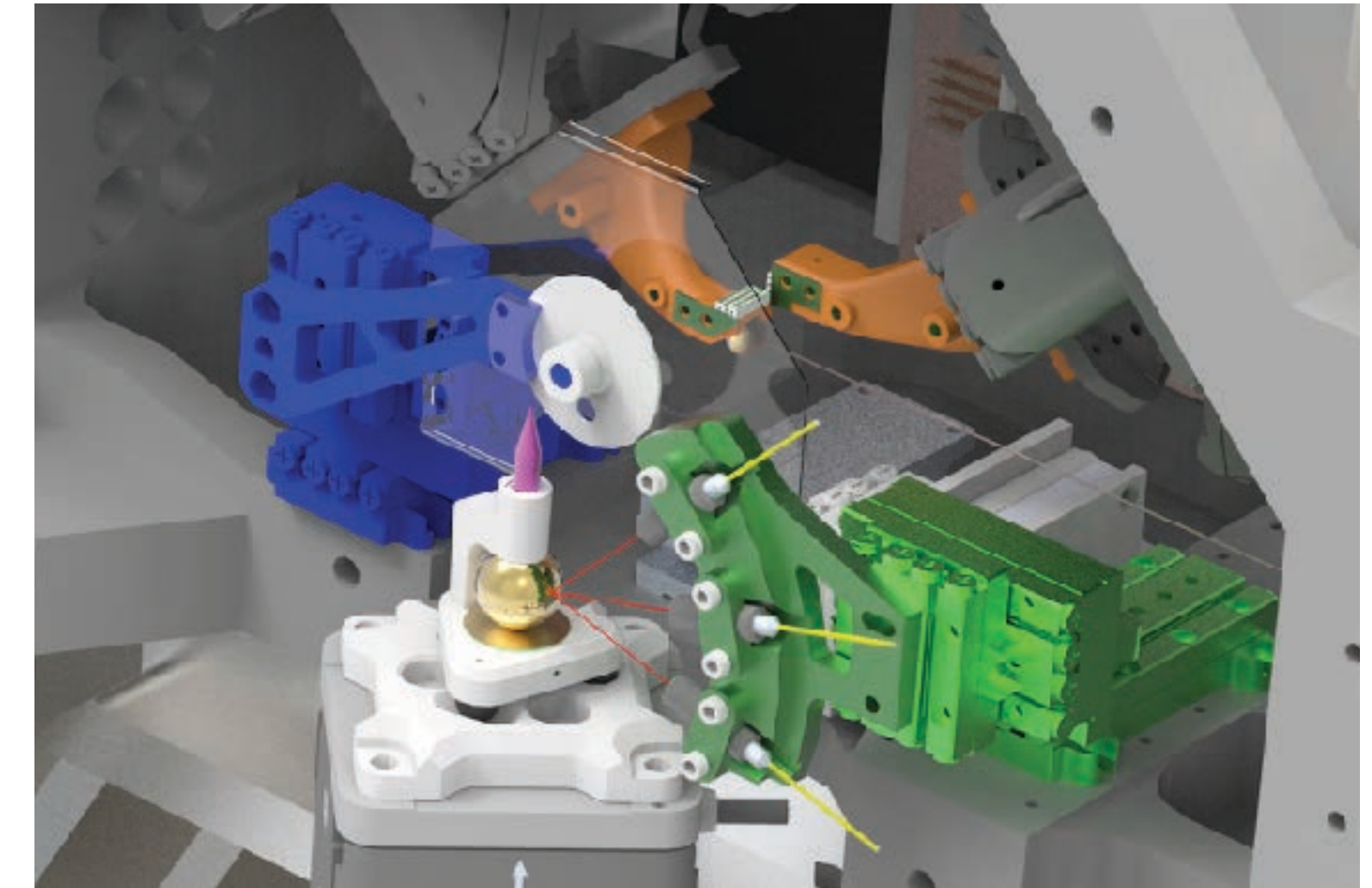
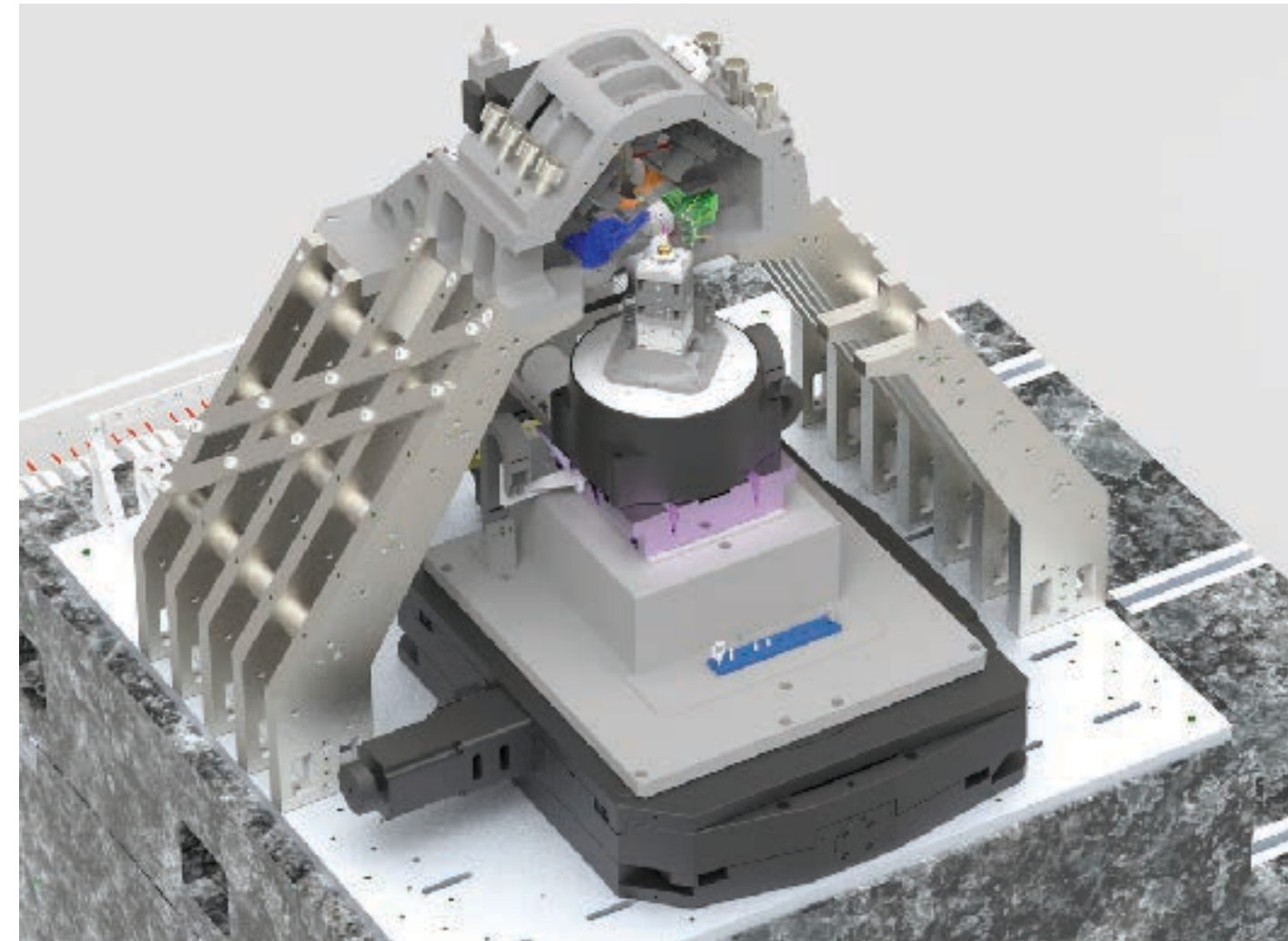
Ptychographic Nano-Analytical Microscope: PtyNAMi

Goals:

- > high spatial resolution
- > high sensitivity
- > 2D and 3D imaging
- > *in situ* & *operando*

Experimental requirements:

- > optimized coherent flux
- > high performance X-ray optics
- > high mechanical stability and control
- > low background



R. Döhrmann, S. Botta, P. Wiljes, H. Lindemann, *et al.*

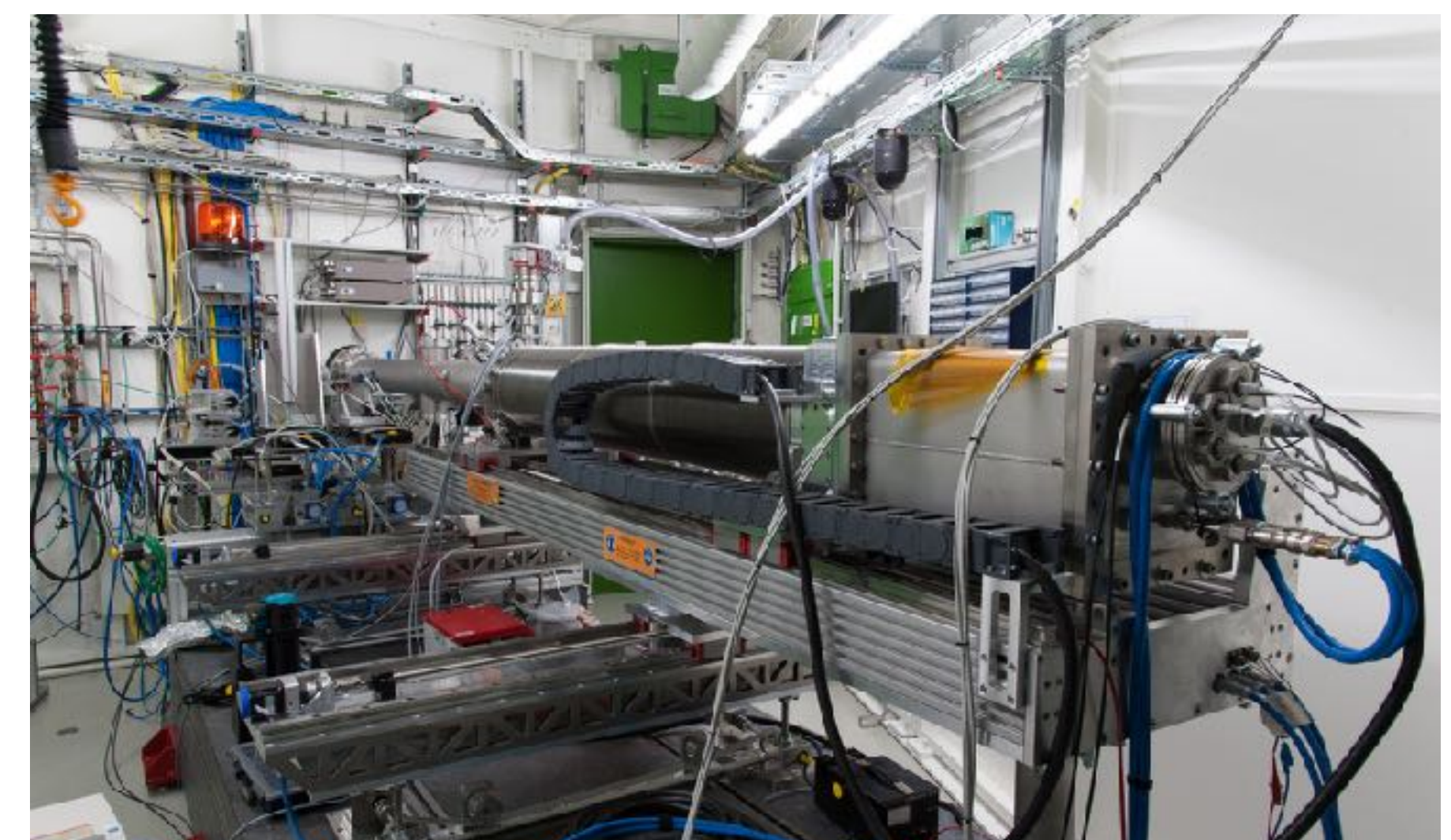
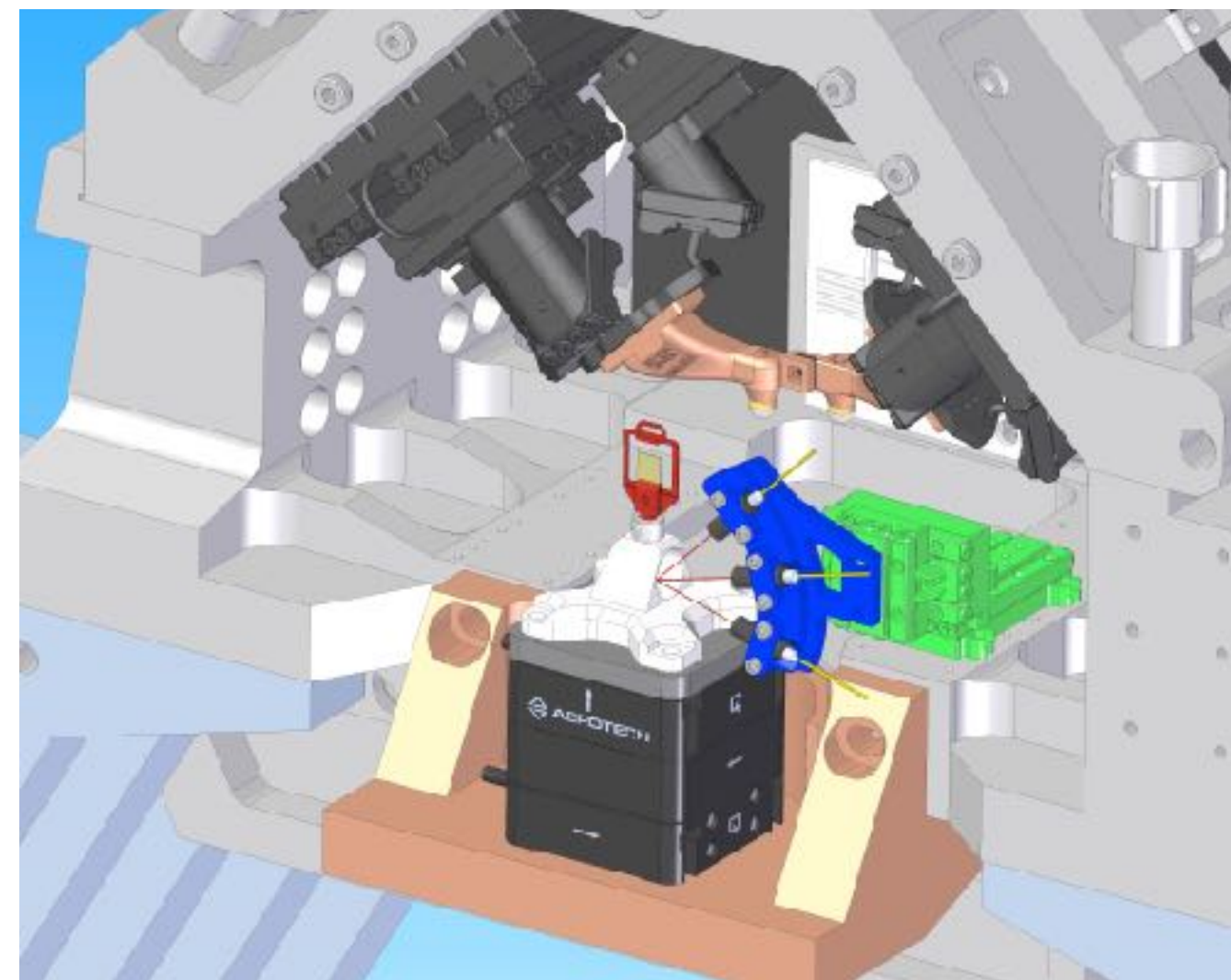
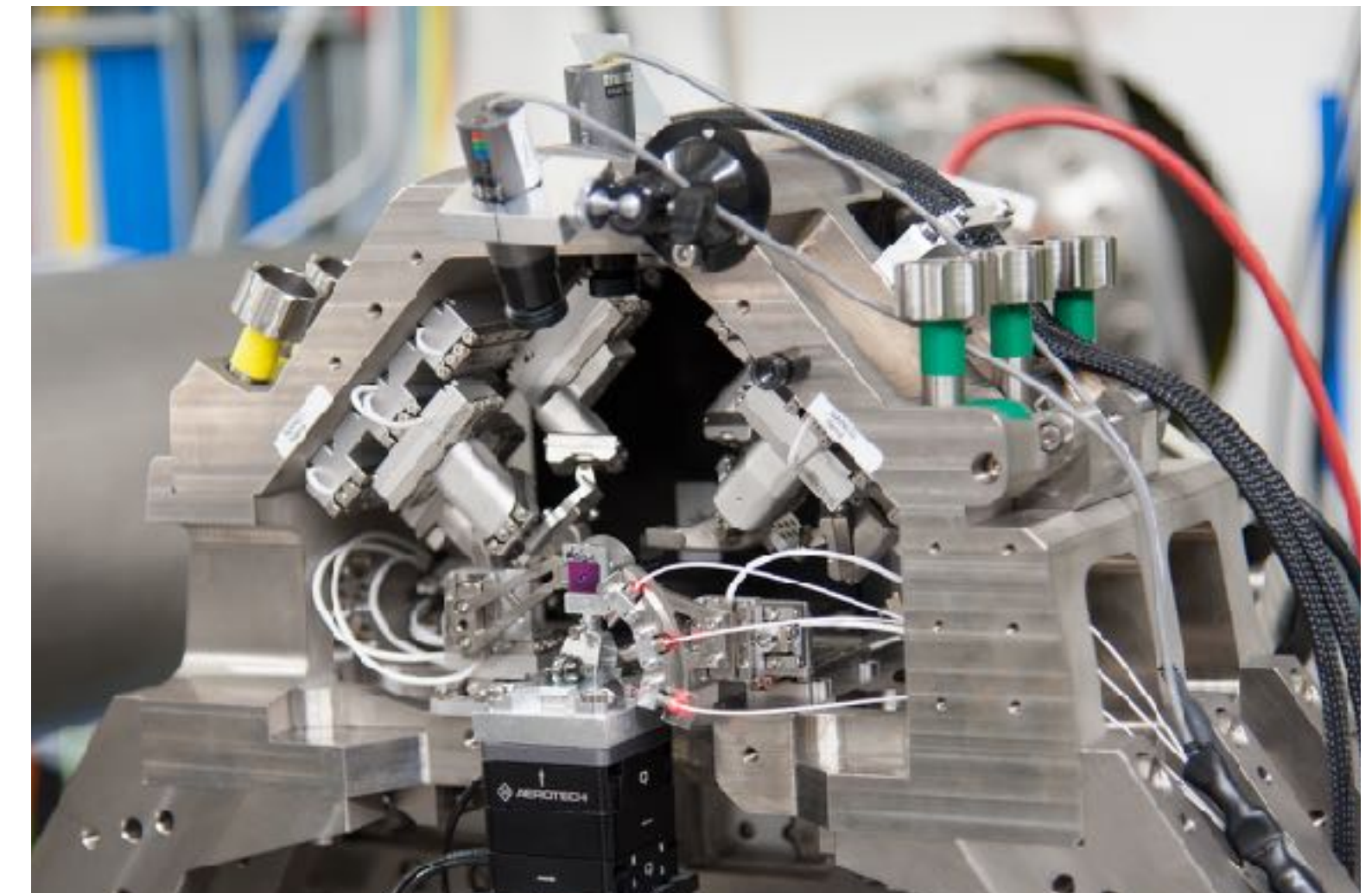
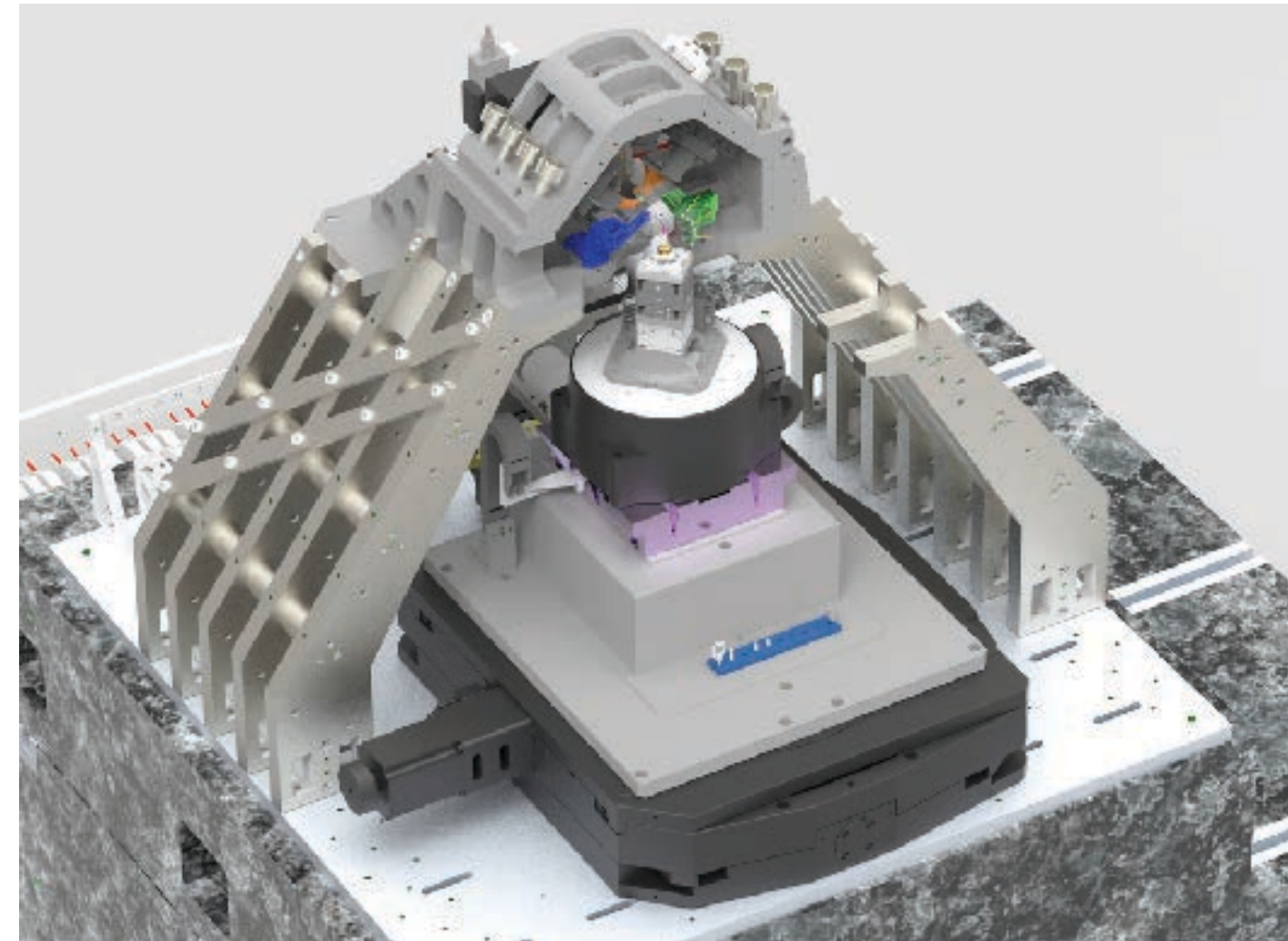
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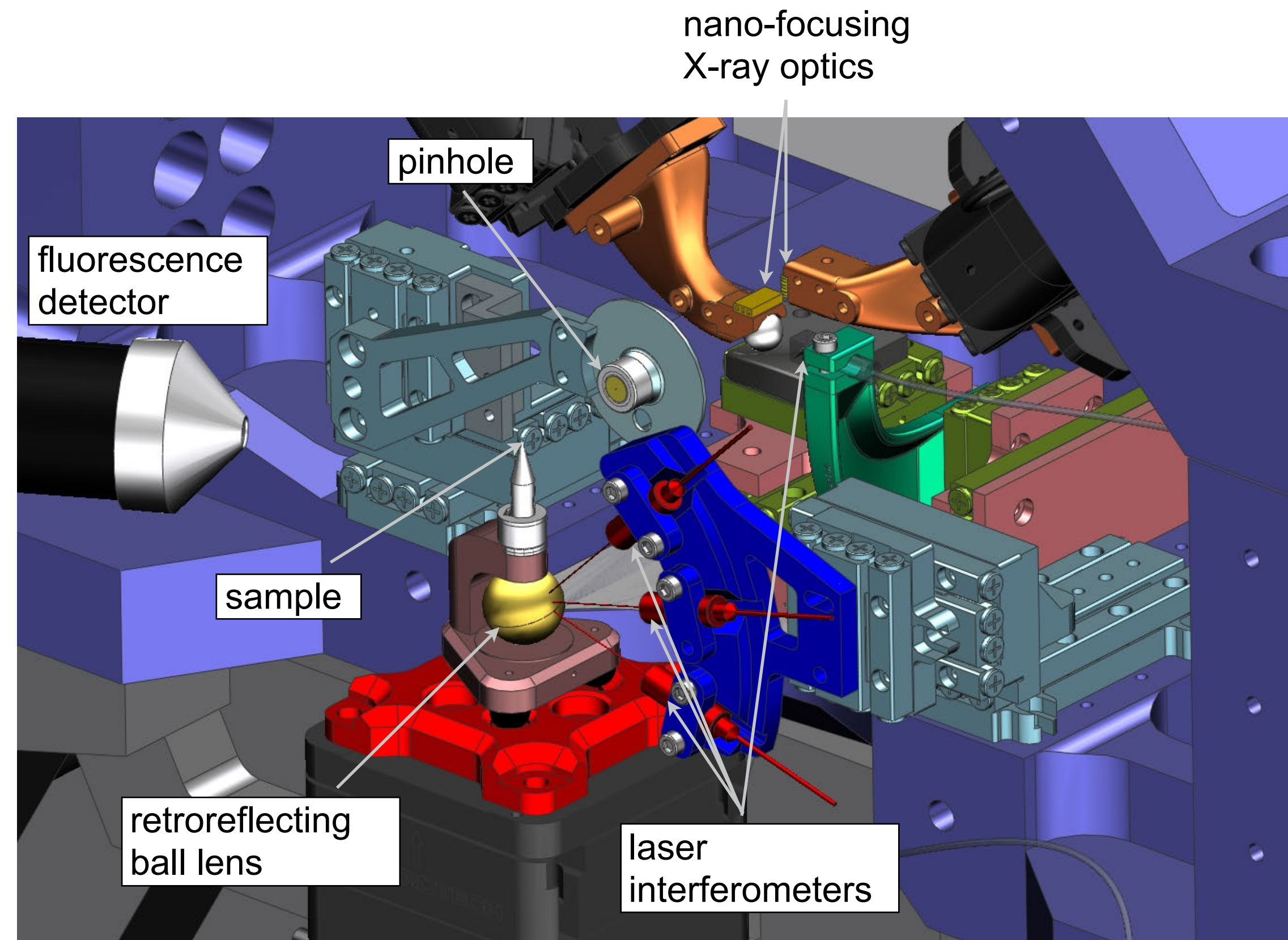
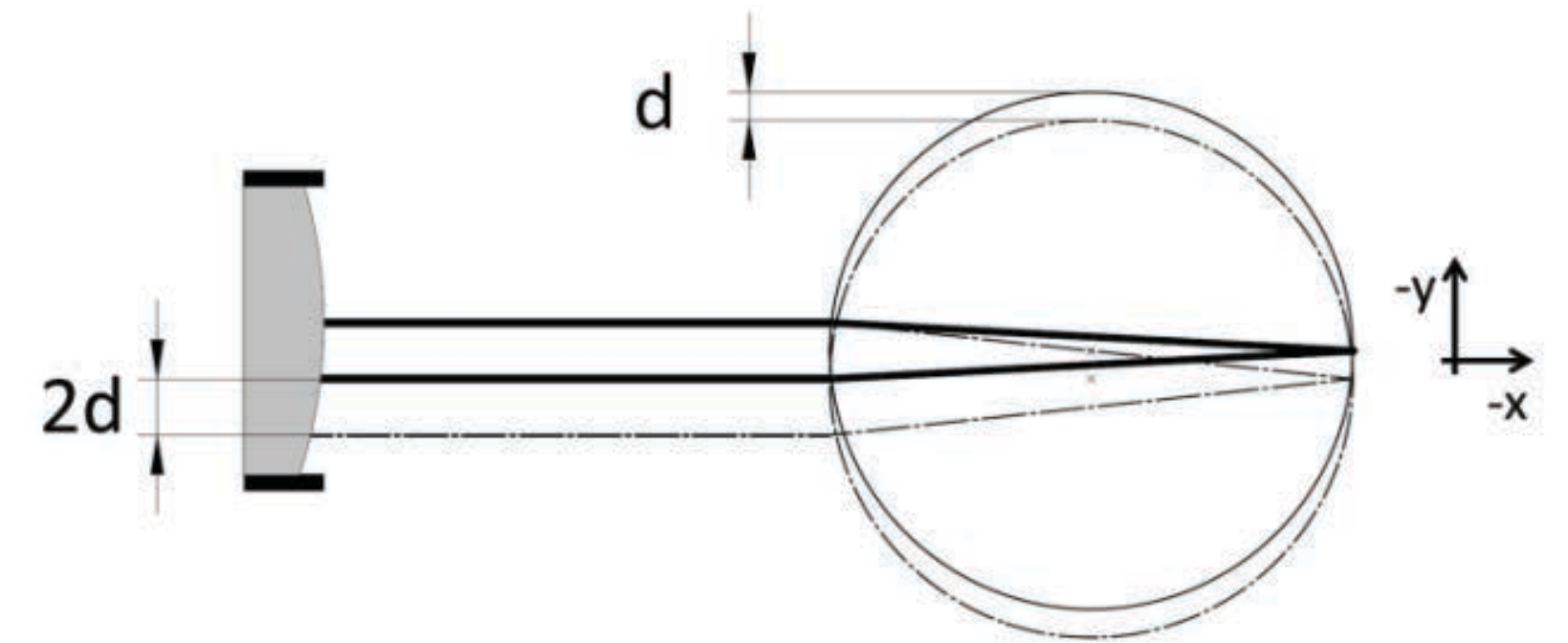
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R. Döhrmann, S. Botta, P. Wiljes, H. Lindemann, *et al.*

PtyNAMI — Optical Interferometers

Sample Environment and Positioning Control



focal length of a ball lens

$$f = \frac{nr}{2(n-1)}$$

$$n = 2 \Rightarrow r = f$$

→ retroreflection

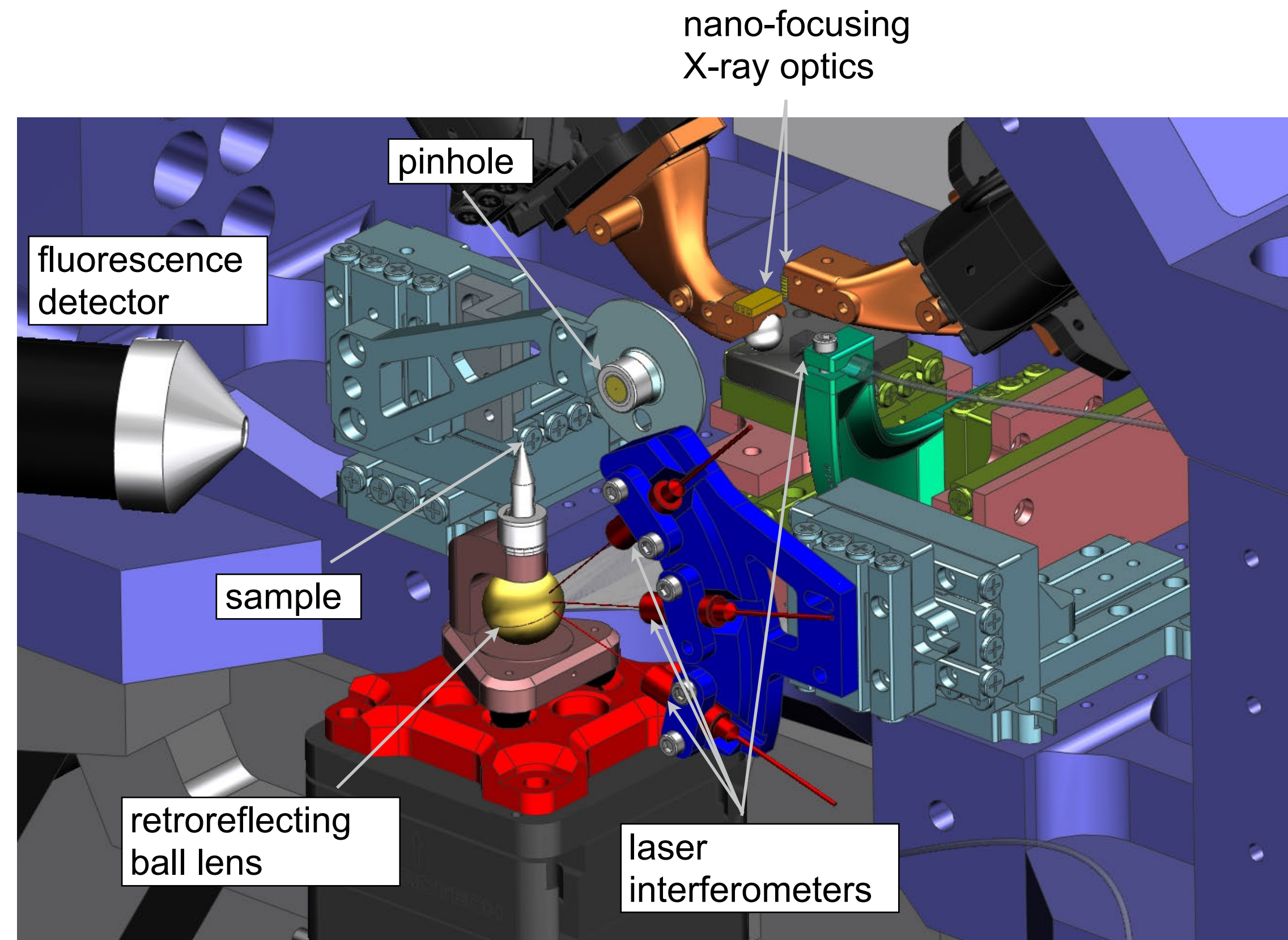
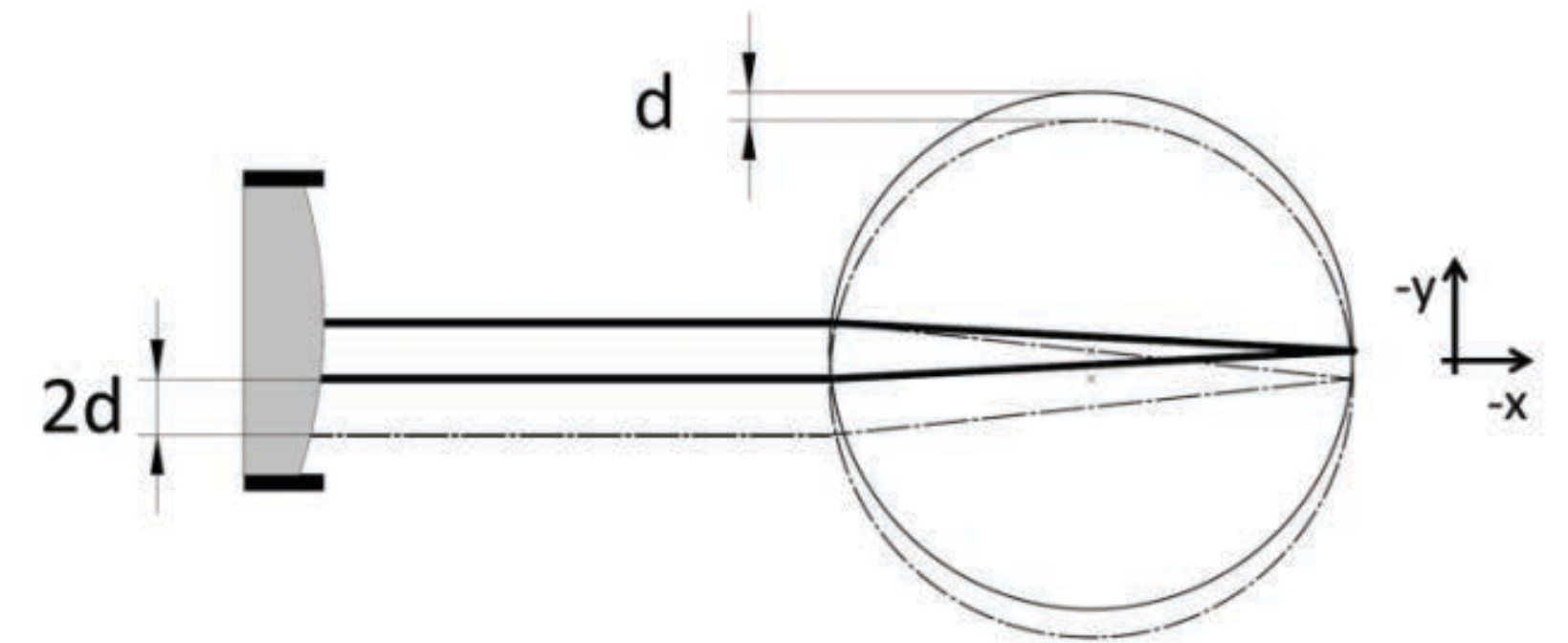
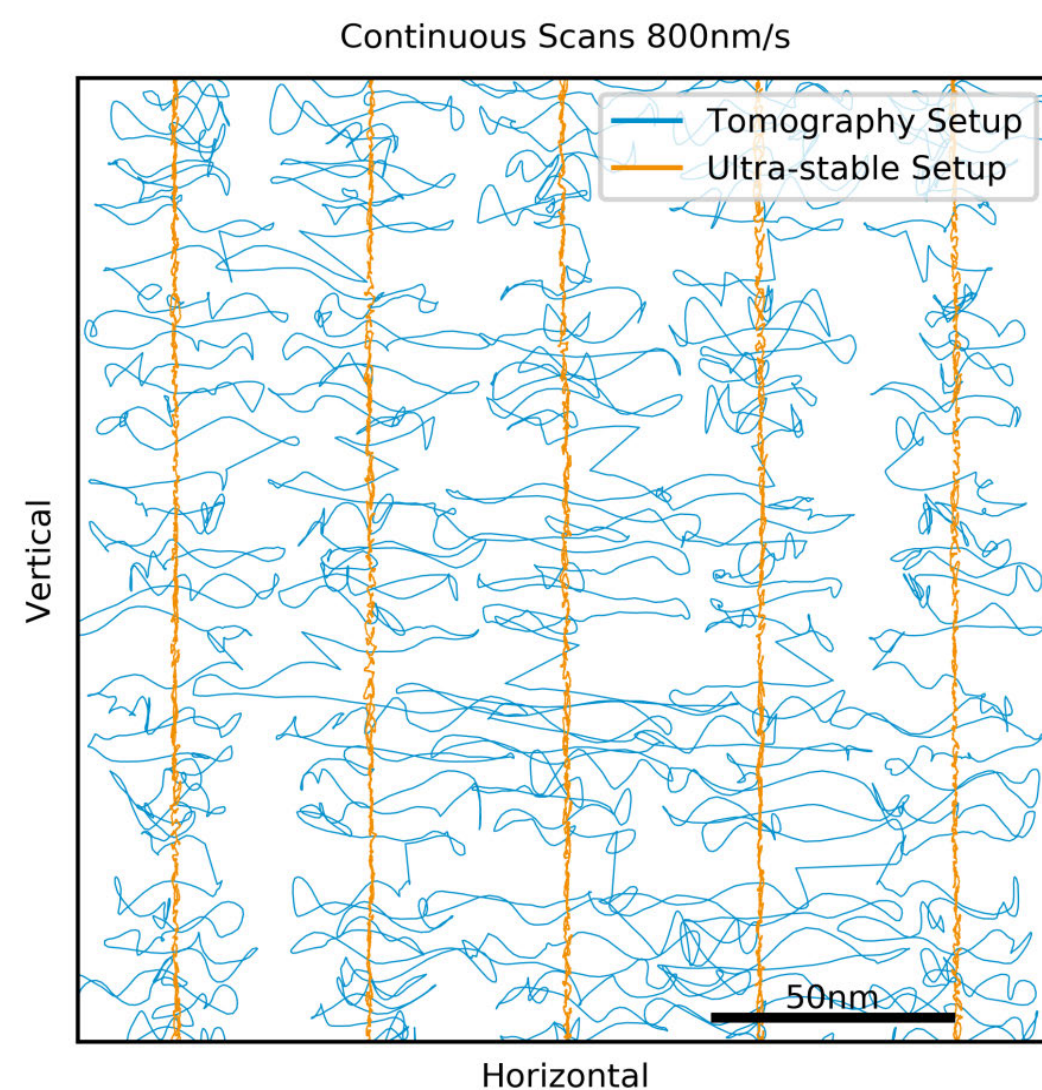
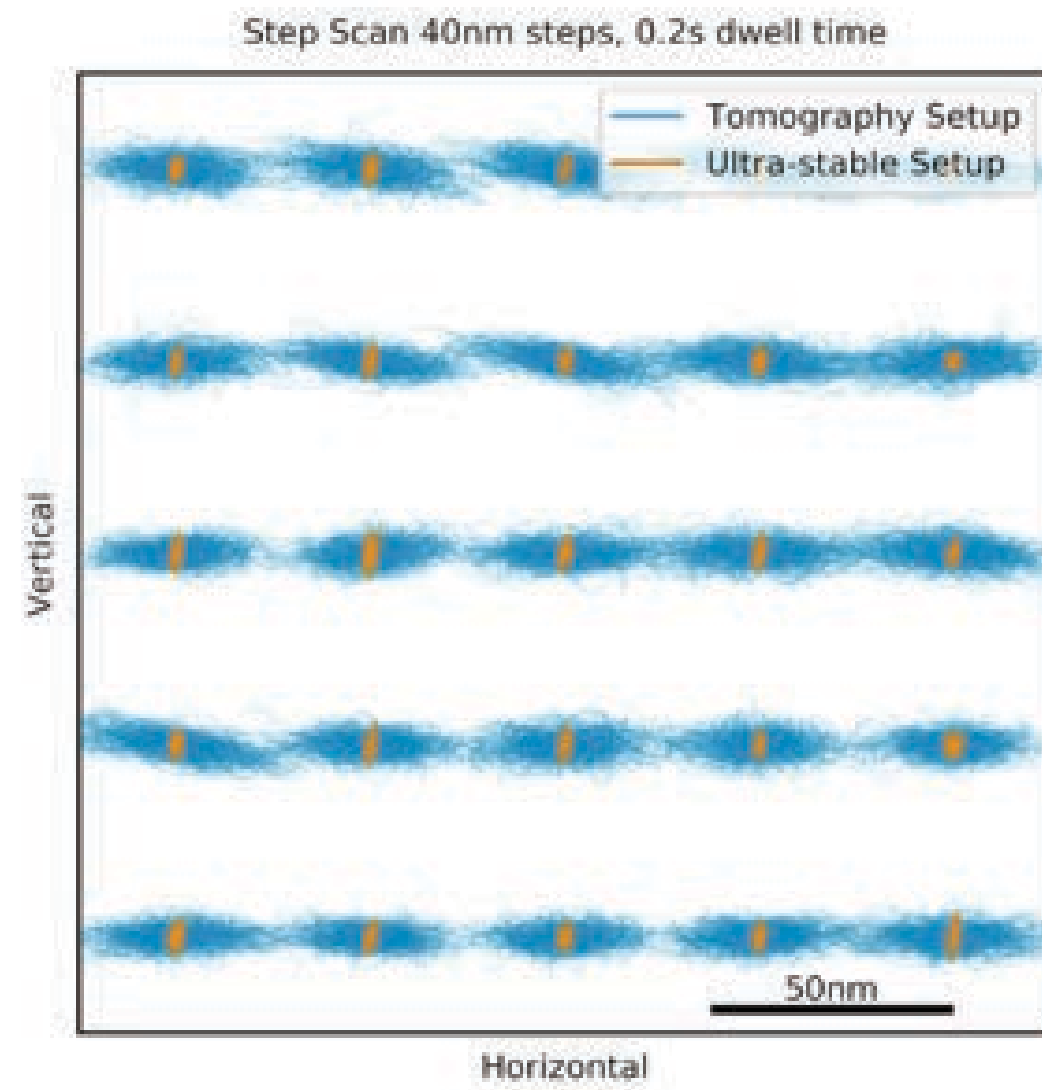
our ball lenses:

$$n = 1.955 @ \lambda = 1550 \text{ nm and } r = 5 \text{ mm}$$

M Seyrich, *et al.*

PtyNAMI — Optical Interferometers

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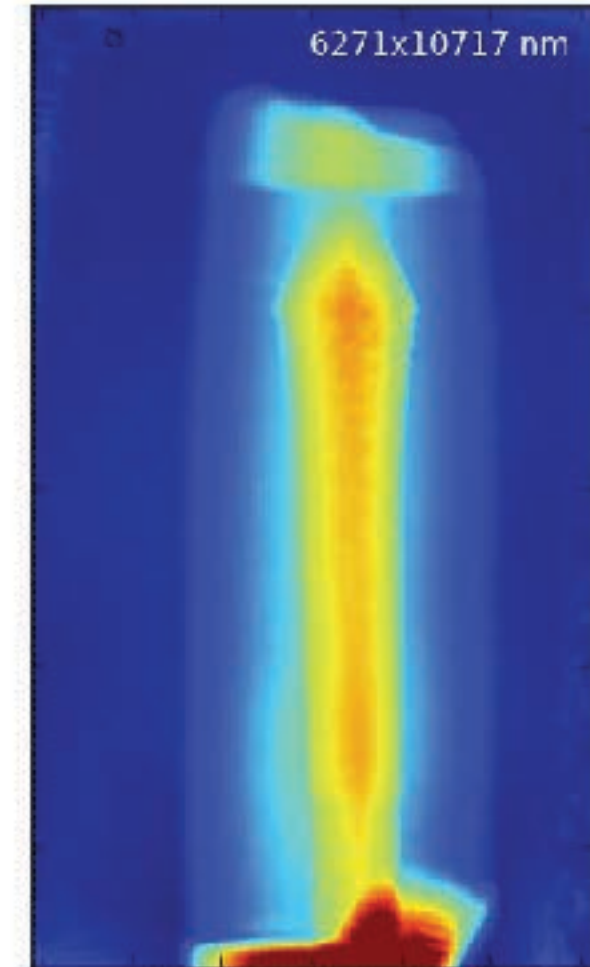
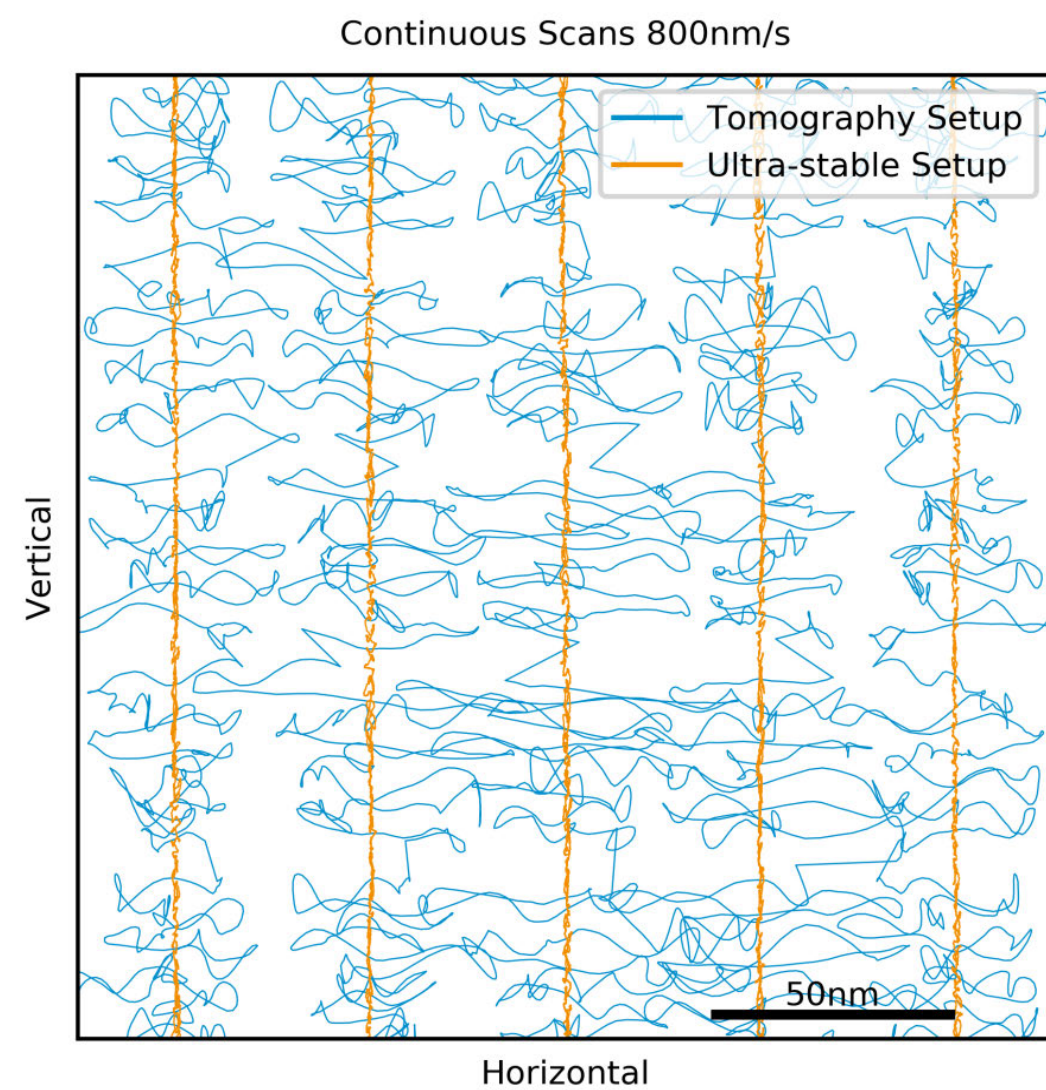
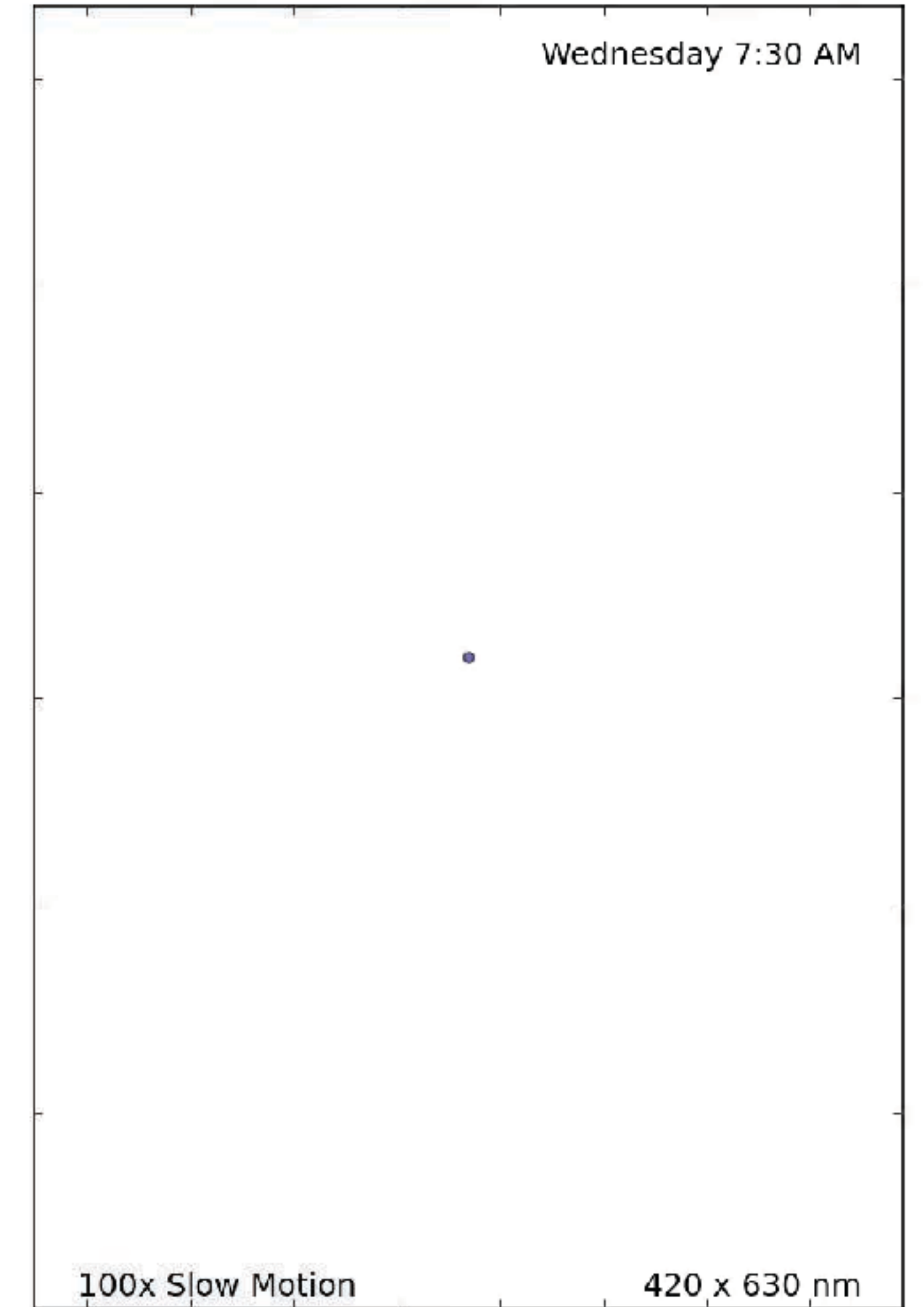
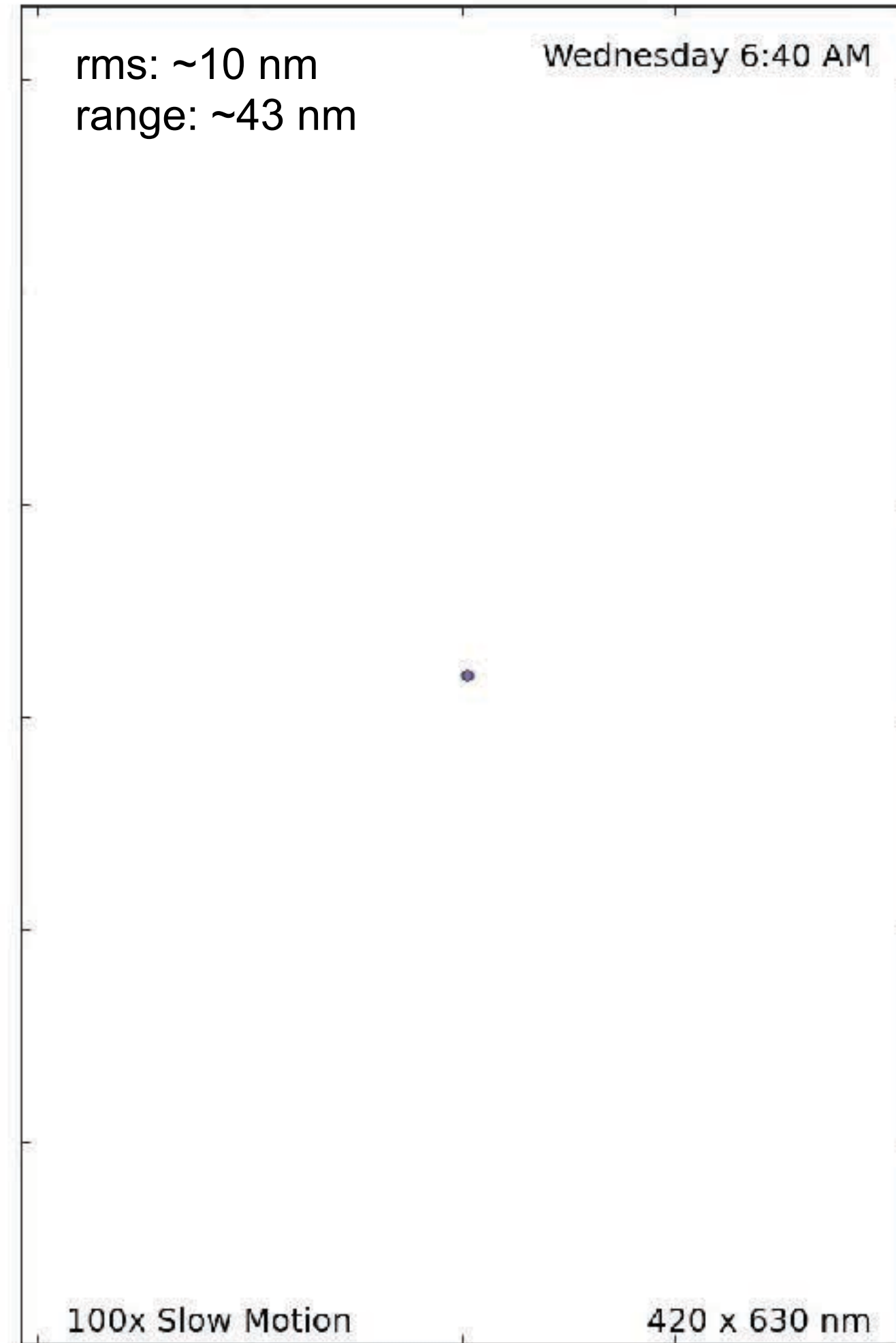
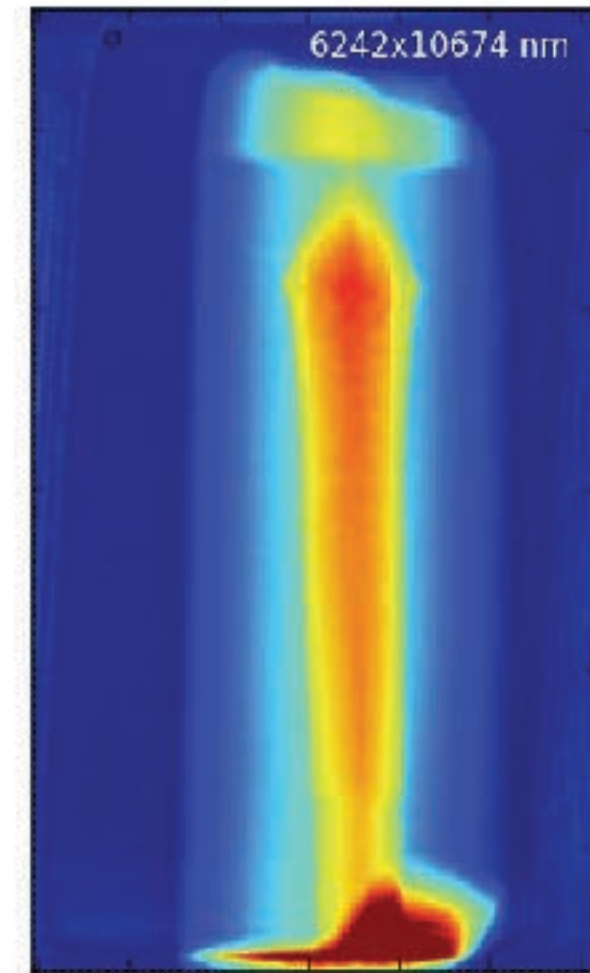
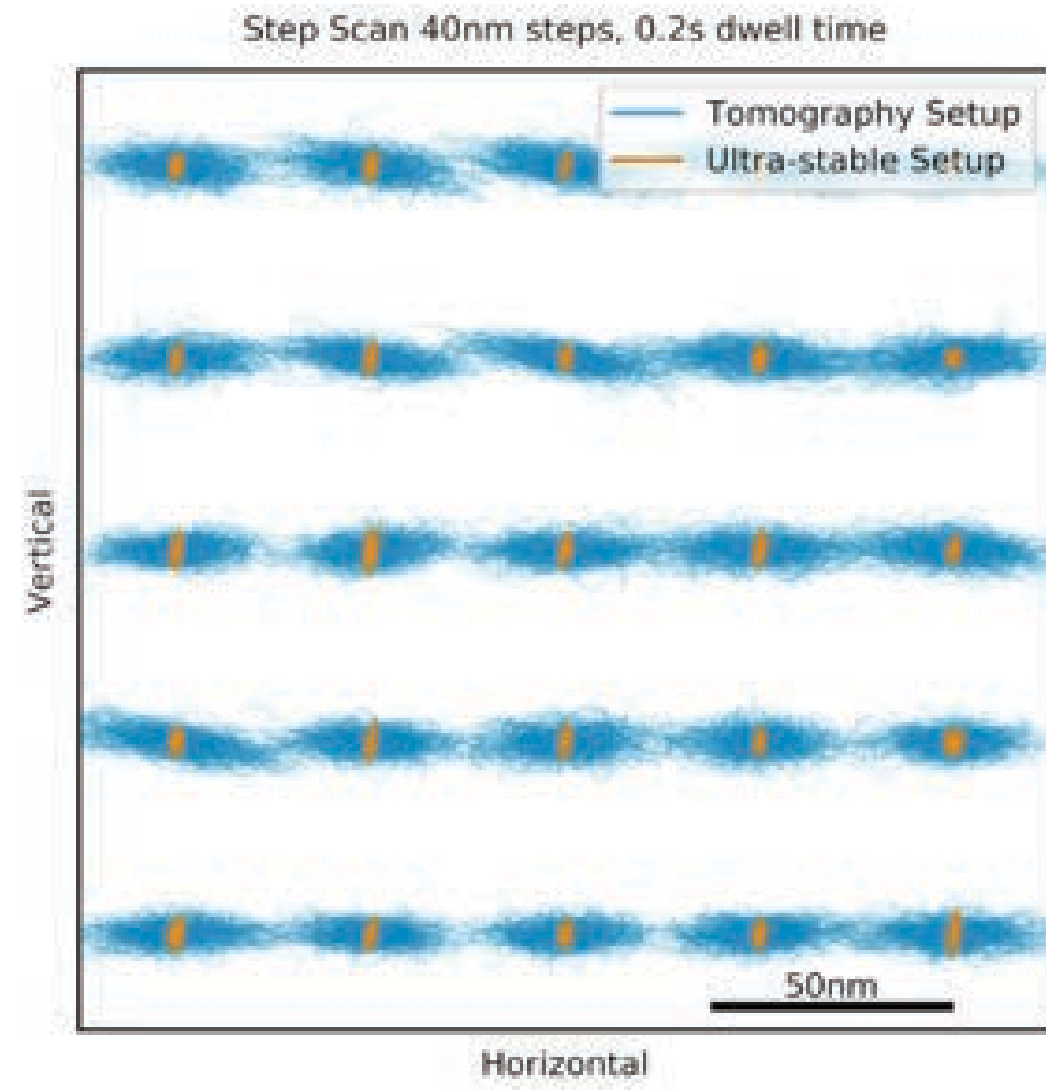
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M Seyrich, *et al.*

PtyNAMI

Sample Environment and Positioning Control

during construction work outside PETRA III

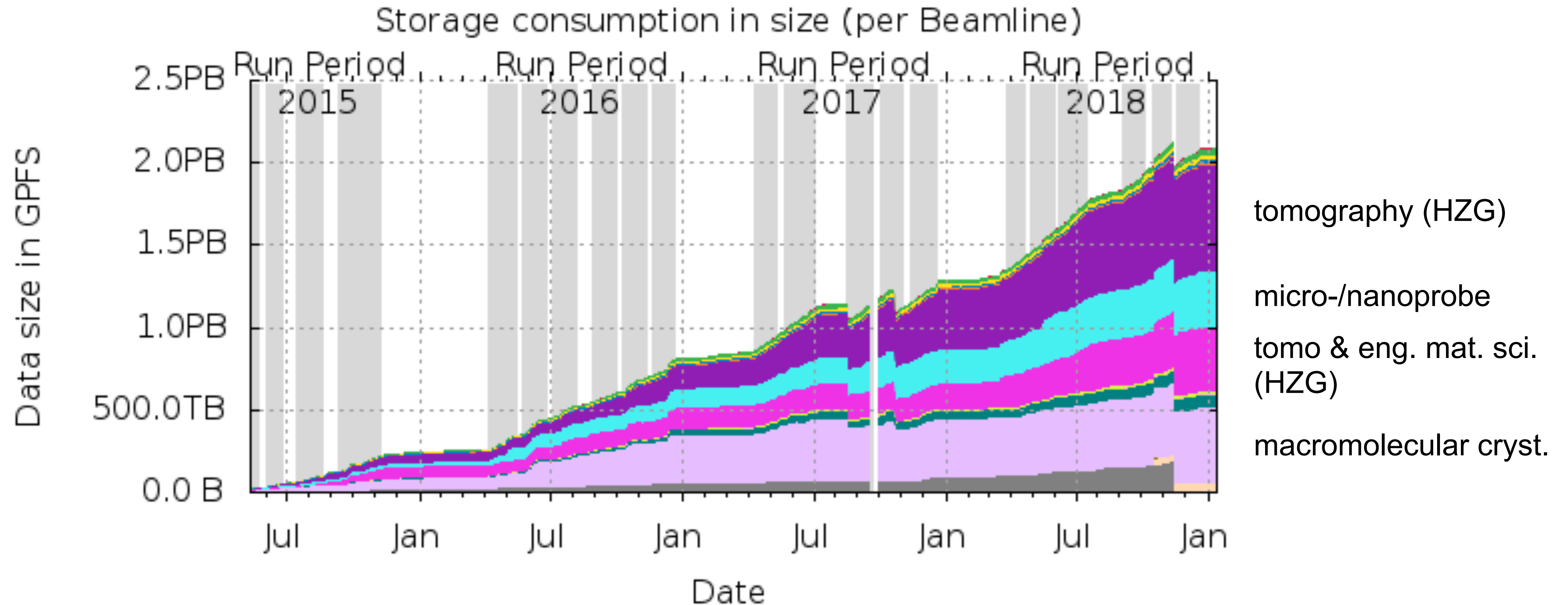


M Seyrich, *et al.*

GPFS: Total Use per Beamline

Data rate increases with development of faster detectors

4 Beamlines generate 80 % of the data on GPFS!

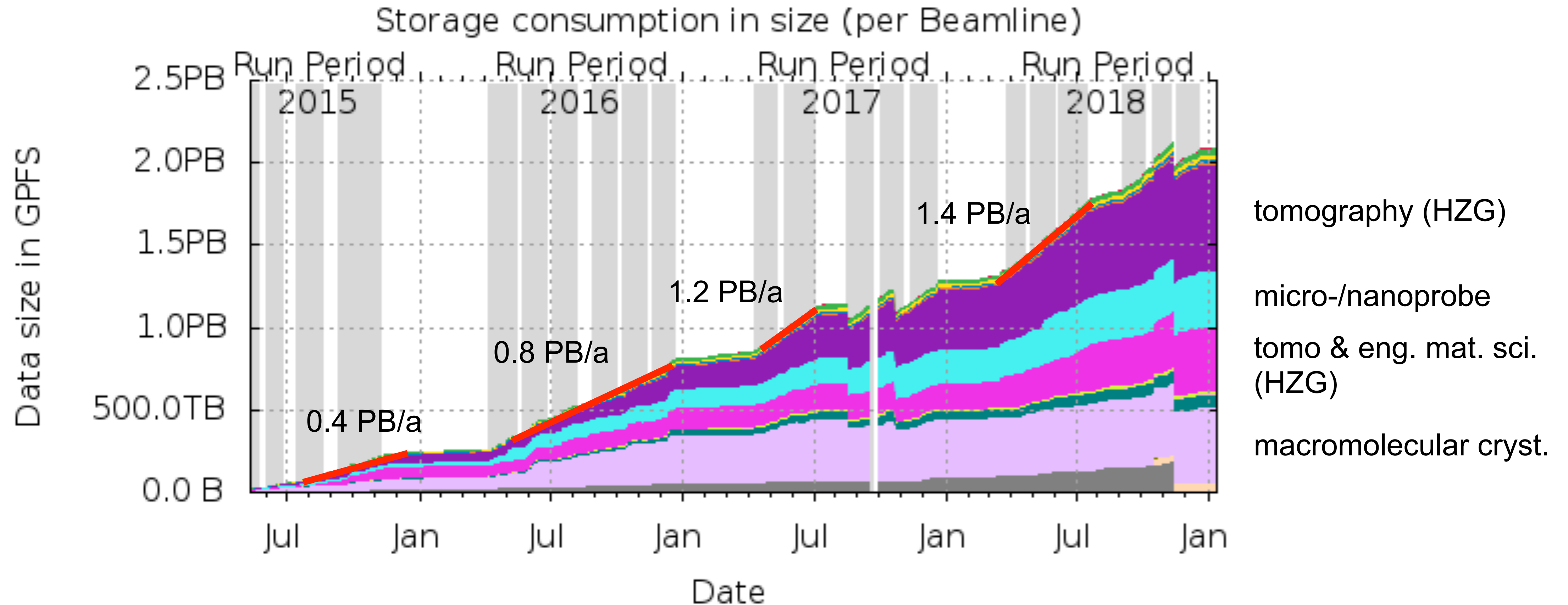


Diffraction detectors running at high full-frame frequencies: “outrunning vibrations”.

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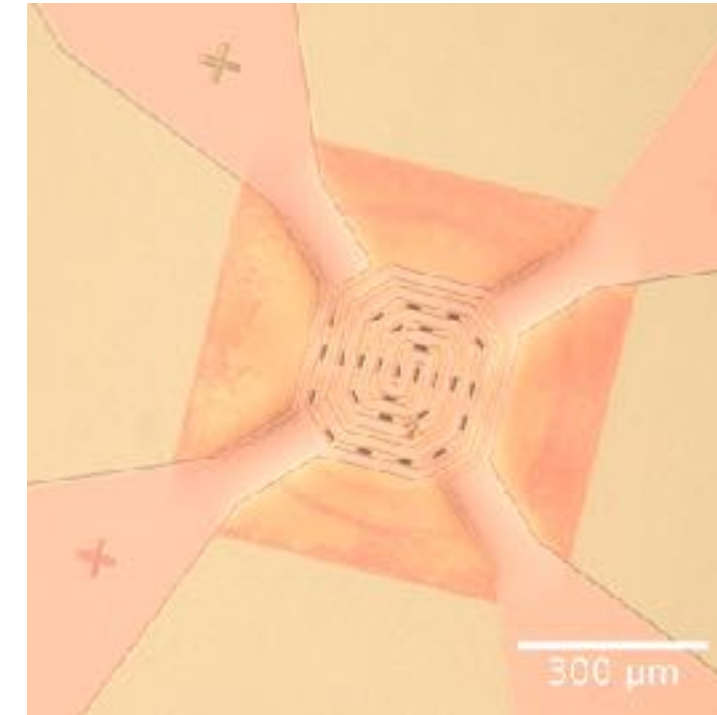
In-situ Ptychography

Example: In-Situ 2D Imaging of Gold Nanoparticles during Thermal Annealing

Why *in situ*?

- > Most materials operate under specific environmental conditions.
- > Uncover chemistry and structure of materials only present under reaction conditions.
- > Reveal relationship between surface structure, materials composition and chemical properties.
- > Imaging: retrieve local structural information in 3D.
- > Design new and better materials.

MEMS-chip

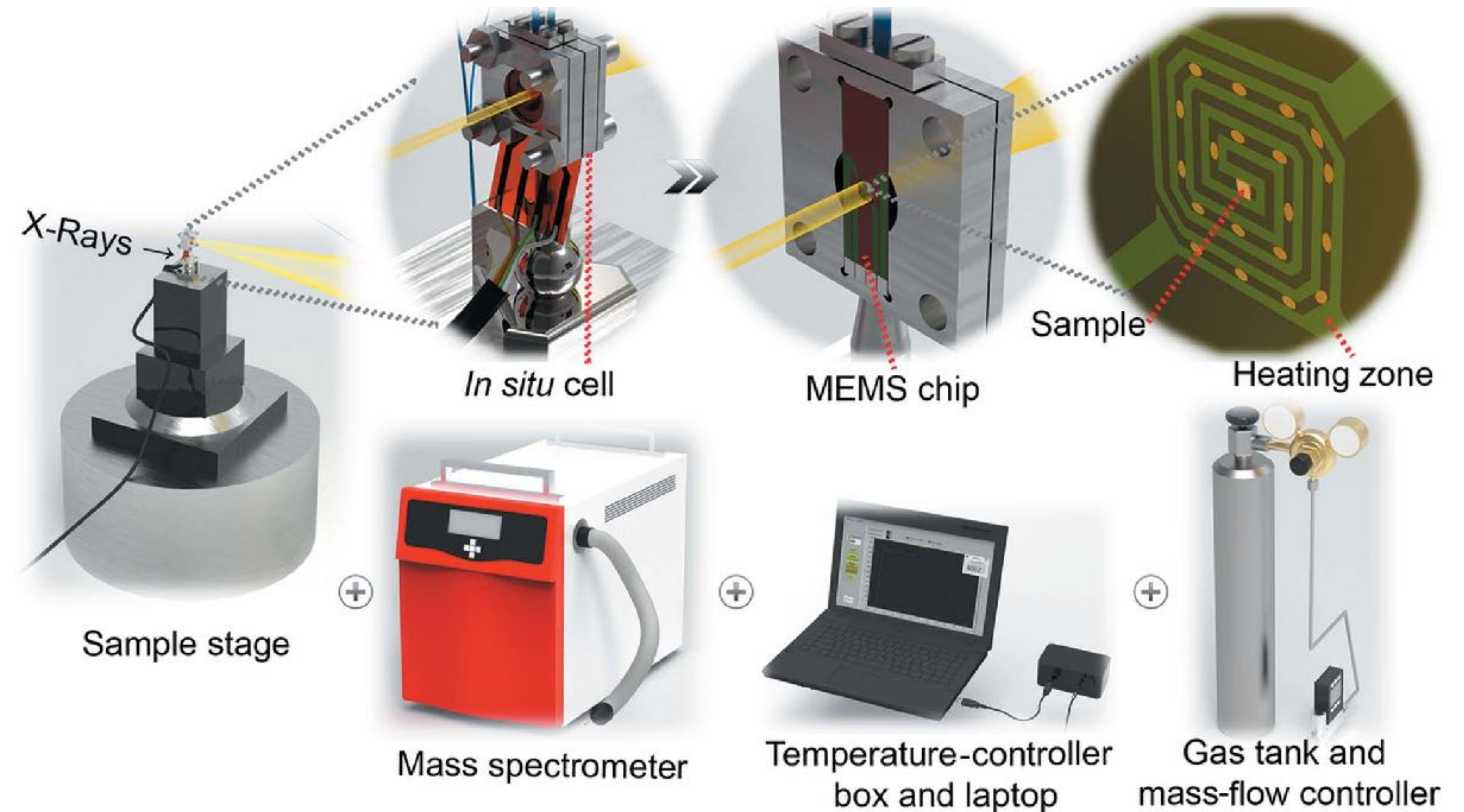


In-situ Cell

In collaboration with KIT: Thomas L. Sheppard, Yakub Fam, Jan-Dierk Grunwaldt, *et al.*

Design requirements:

- > small device to minimize the load on the piezoscanner (positioning accuracy)
- > remote temperature control
- > remote mass-flow control
- > mass spectrometer for gas analysis
- > compatible to limited-angle tomographic applications



Y. Fam, *et al.*, *J. Synchrotron Rad.* **26**, 1769-1781 (2019).

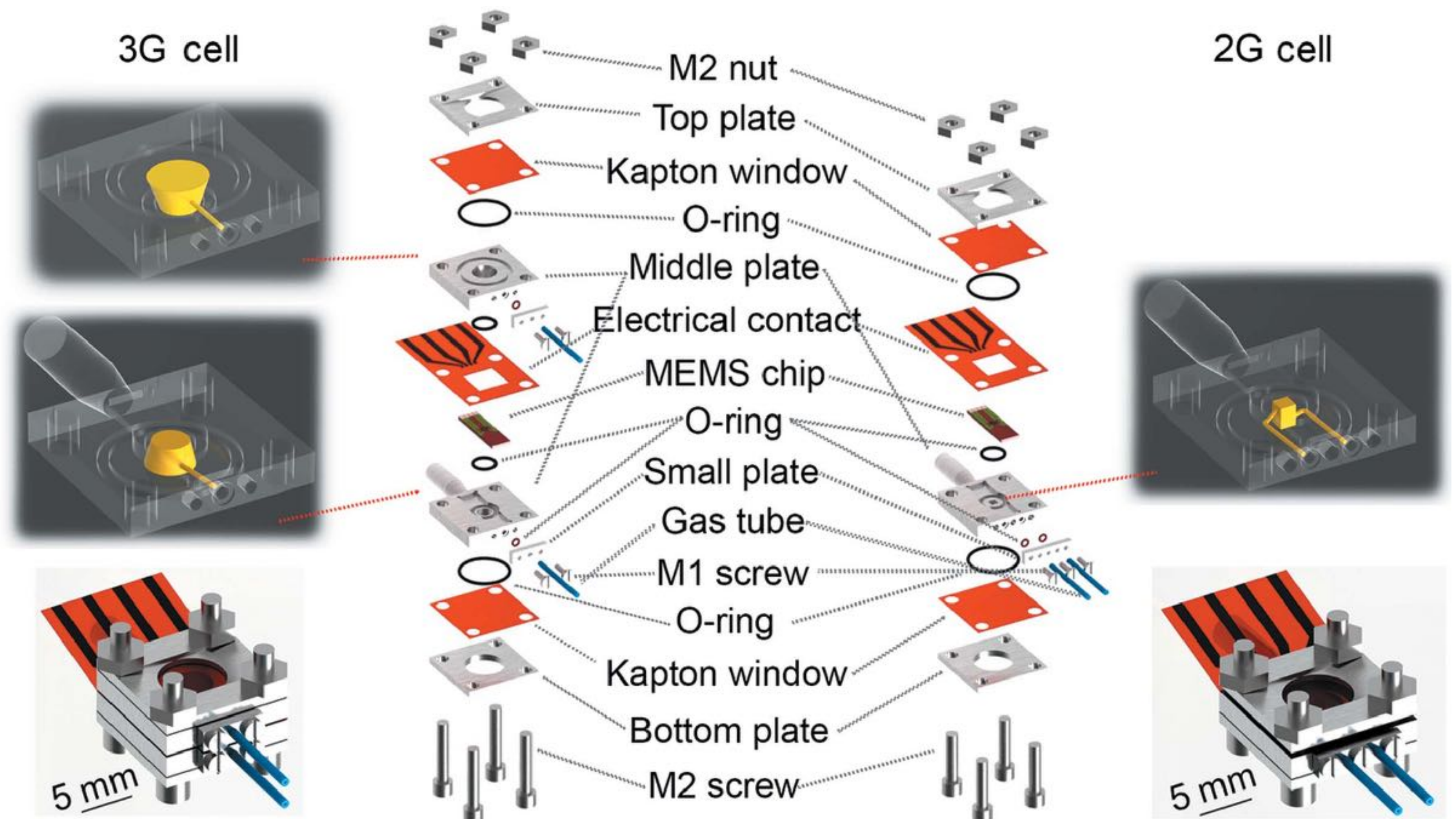
Different Generations of *In-situ* Cells

In collaboration with KIT: Thomas L. Sheppard, Yakub Fam, Jan-Dierk Grunwaldt, *et al.*

Cell design:

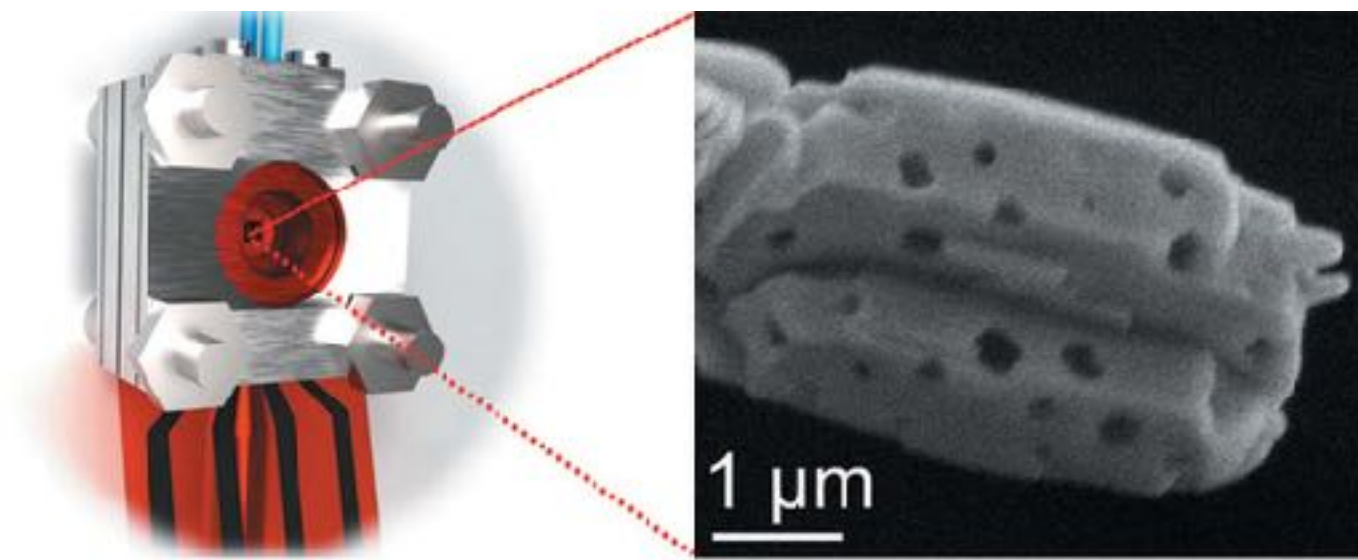
- > based on commercial MEMS-chips
- > temperature control up to 1573K
- > pressure up to 100kPa
- > compatible with hard X-ray ptychography and transmission electron microscopy

Multiple generations of cells have been designed and tested!



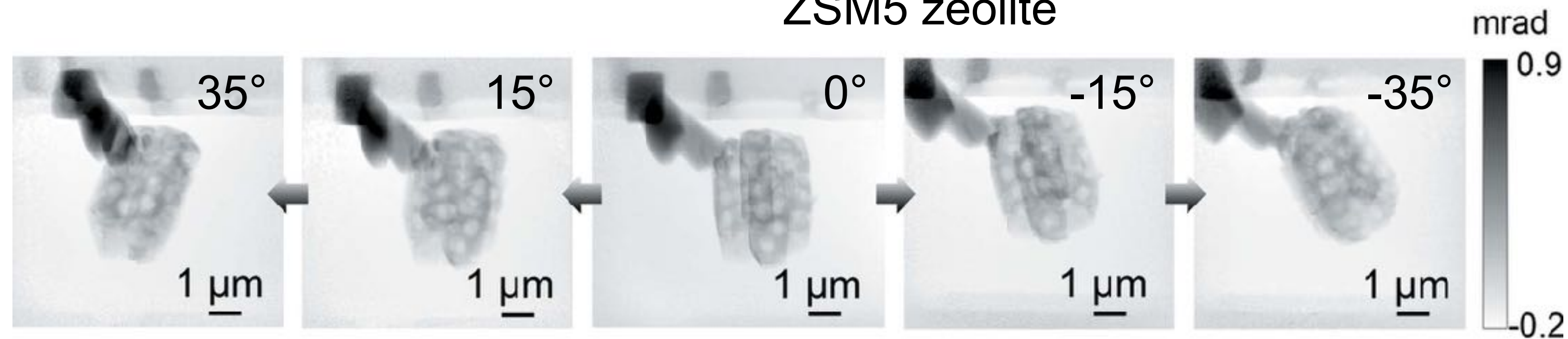
Y. Fam, *et al.*, *J. Synchrotron Rad.* **26**, 1769-1781 (2019).

Limited-Angle Ptychography *In Situ*



Accessible angular range limited to about $\pm 35^\circ$

ZSM5 zeolite



deep learning

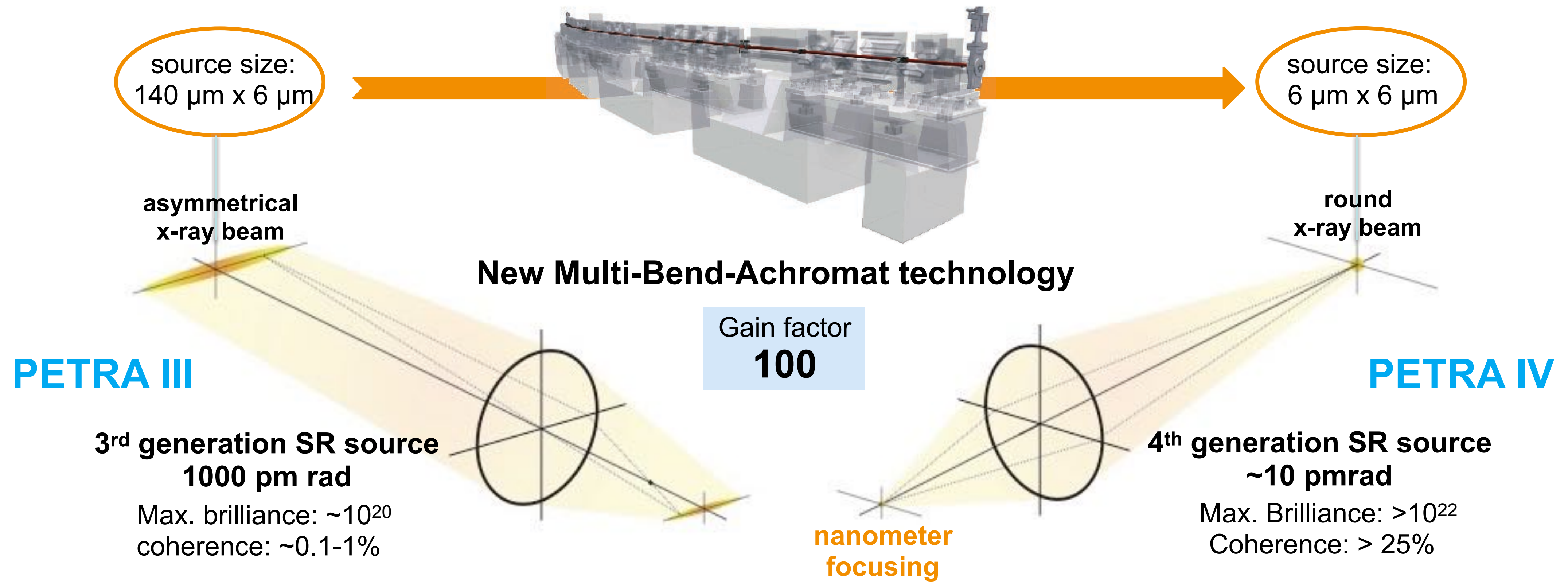


SART



Y. Fam, *et al.*, *J. Synchrotron Rad.* **26**, 1769-1781 (2019).

Perspectives: PETRA IV



PETRA IV

- > new multi-bend-achromat (MBA) technology +
- > 2.3 km circumference (largest SR source)
emittance scales as $1/(\text{circumference})^3$
- diffraction limited down to a wavelength of 1 Å (ultimate storage ring)

Qualitative step in synchrotron analytics

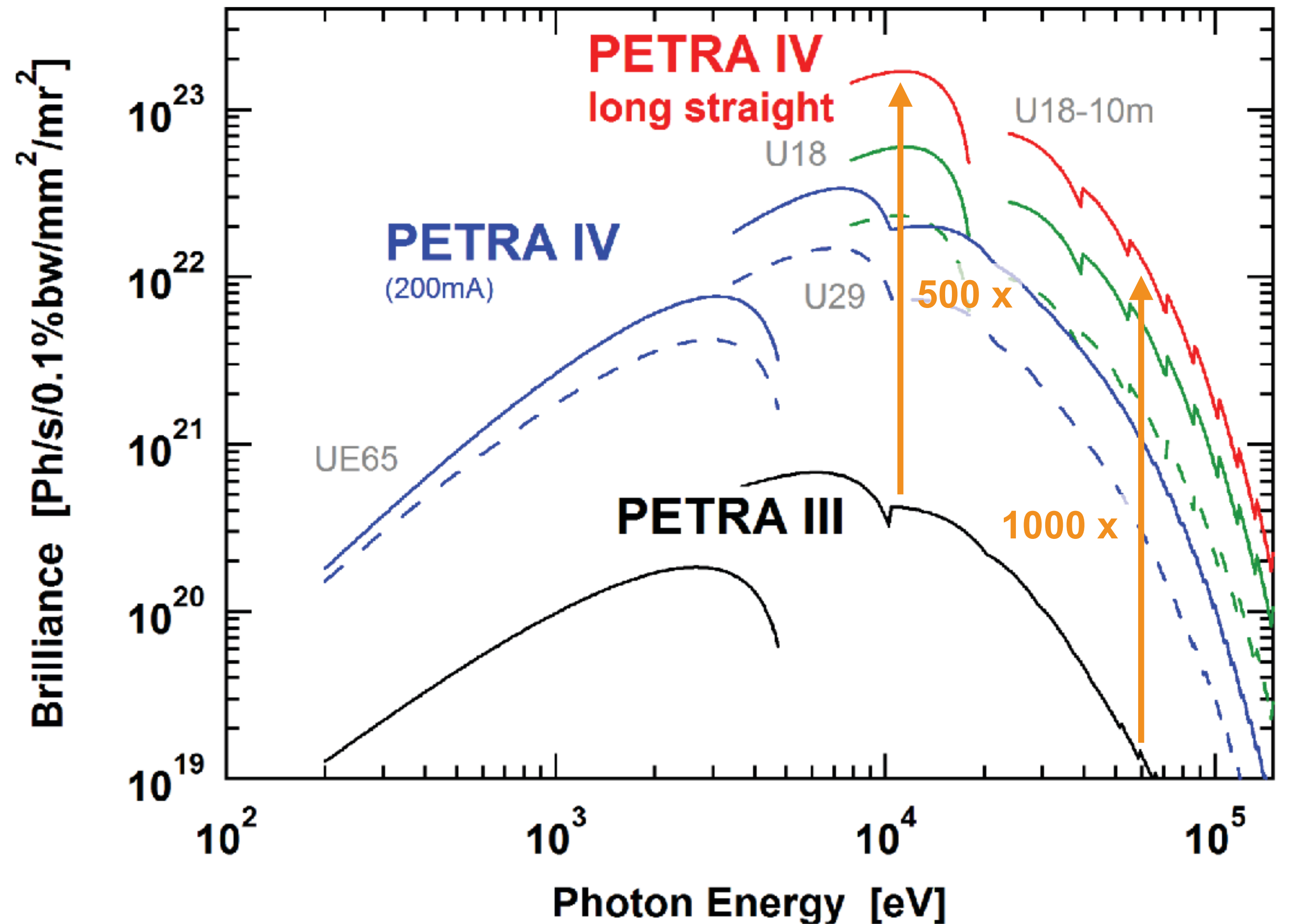
In-situ 3D-microscopy on nanometer scale

Operando nanoimaging of

- > structure, chemistry
- > electronic and magnetic properties
- > dynamics on the sub-nanosecond scale

PETRA IV

Expected Brightness



Based on current design:

> emittance:

→ coherence mode: < 20 x 4 pmrad²

→ timing mode: < 50 x 10 pmrad²

> undulators: 5 m, 10 m

> optimized beta (in 10 m section): 2 x 2 m²

> ring current: 200 mA

Brightness increase by

→ 500 x (hard X-rays)

→ 1000 x (high-energy X-rays)

PETRA IV brightness at 100 keV
same as for 10 keV at PETRA III today!!

C. G. Schroer, et al., JSR **25**, 1277 (2018).

Summary and Outlook

PtyNAMI

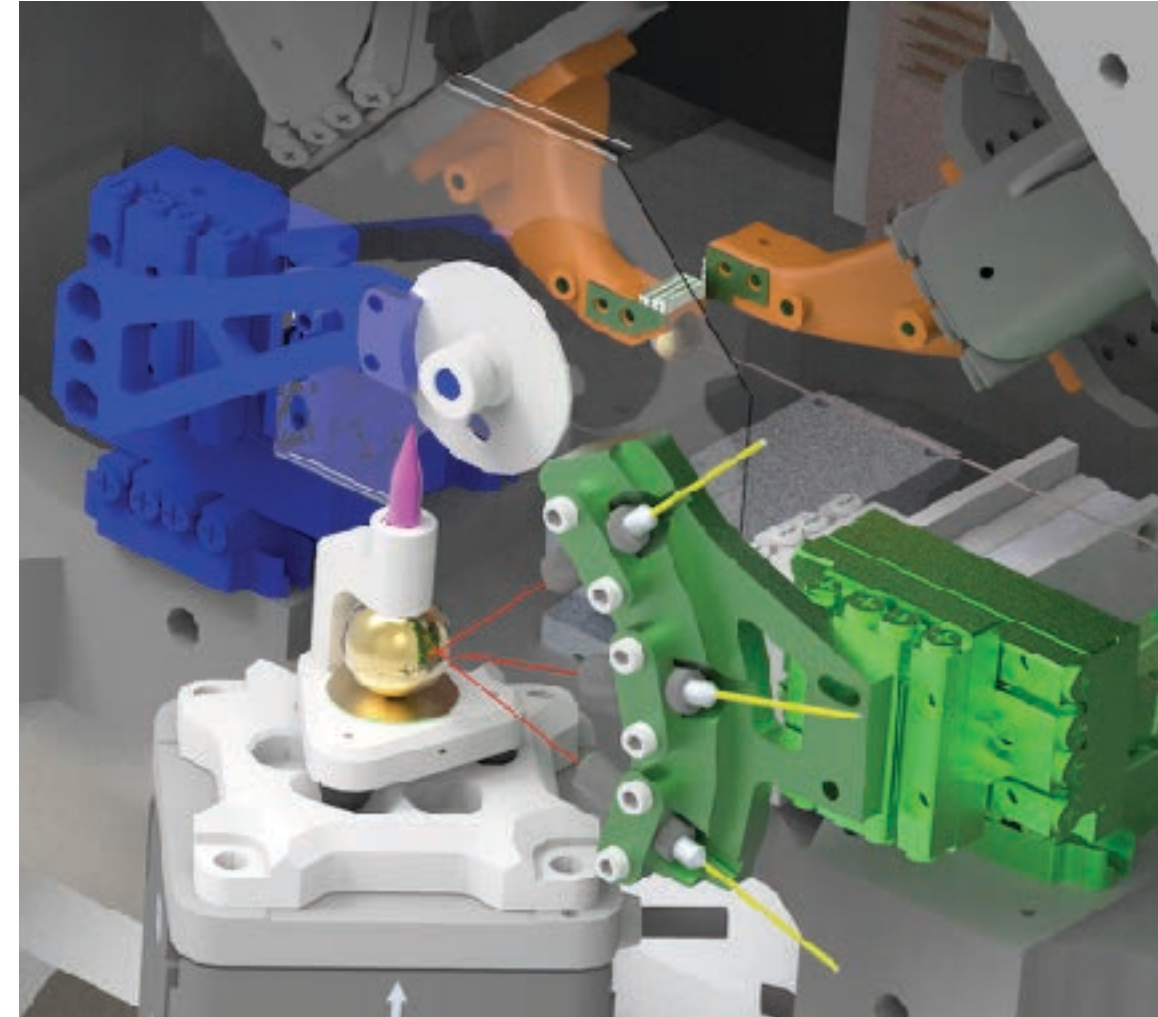
- > optimize coherent flux
- > high-performance X-ray optics
- > high mechanical stability and control
- > low scattering background

In-situ cell developments at beamline P06

- > based on commercial MEMS-chips
- > temperature and pressure control, gas analysis
- > limited-angle ptychographic tomography
- > compatible with hard X-ray ptychography and transmission electron microscopy

Diffraction-Limited Storage Rings

- > high coherent photon flux:
fast in-situ hard X-ray microscopy with high spatial resolution (towards 1nm)



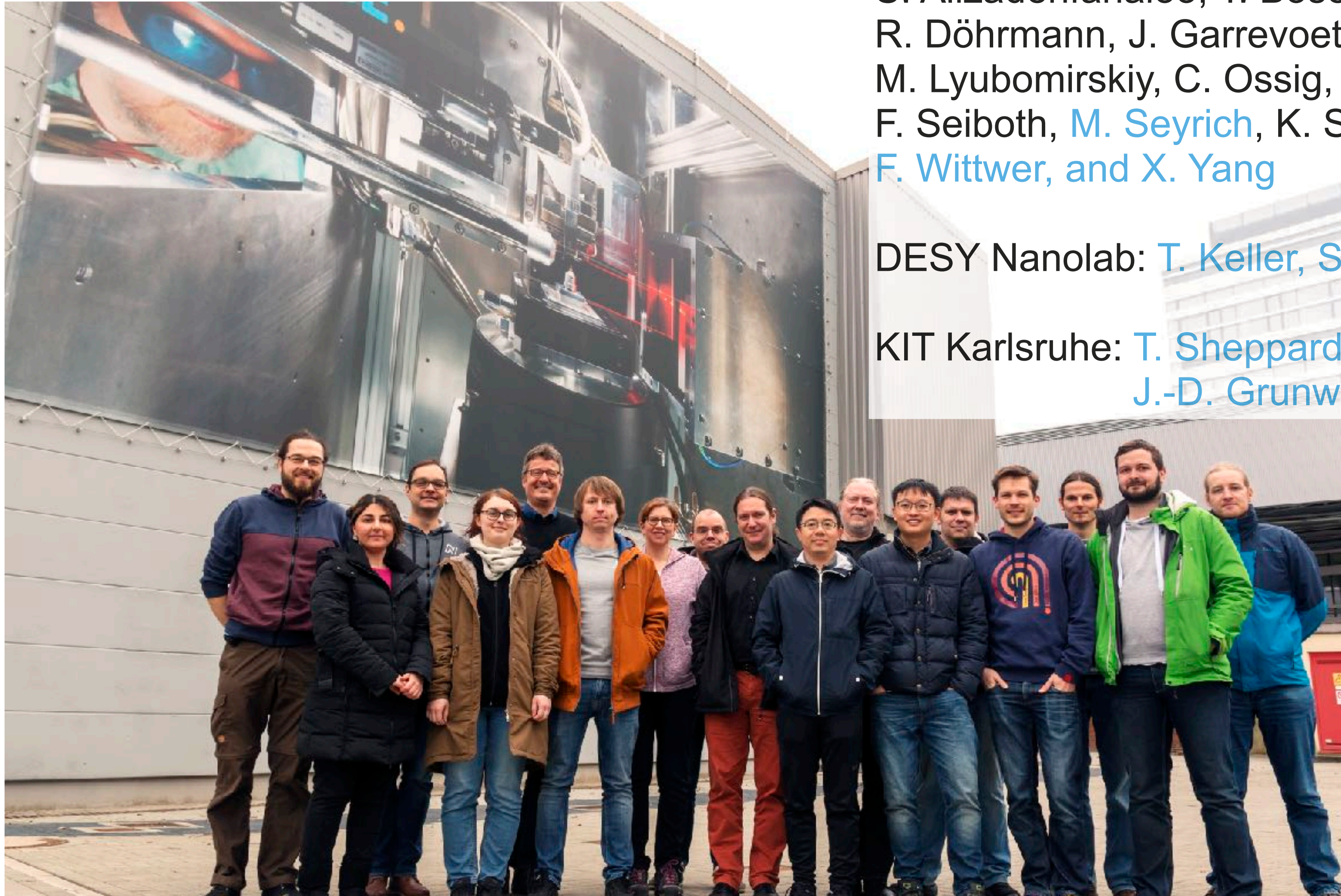
Acknowledgements

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DESY Nanolab: T. Keller, S. Kulkarni, A. Stierle

KIT Karlsruhe: T. Sheppard, Y. Fam, J. Becher, S. Weber, and
J.-D. Grunwaldt



Thank you very much for your attention!



PETRA Extension
Ada Yonath Hall

CHyN

HARBOR

MPI-SD



CXNS
NanoLab

CMWS

PETRA III

FLASH

PETRA Extension
Paul Peter Ewald-Hall

